

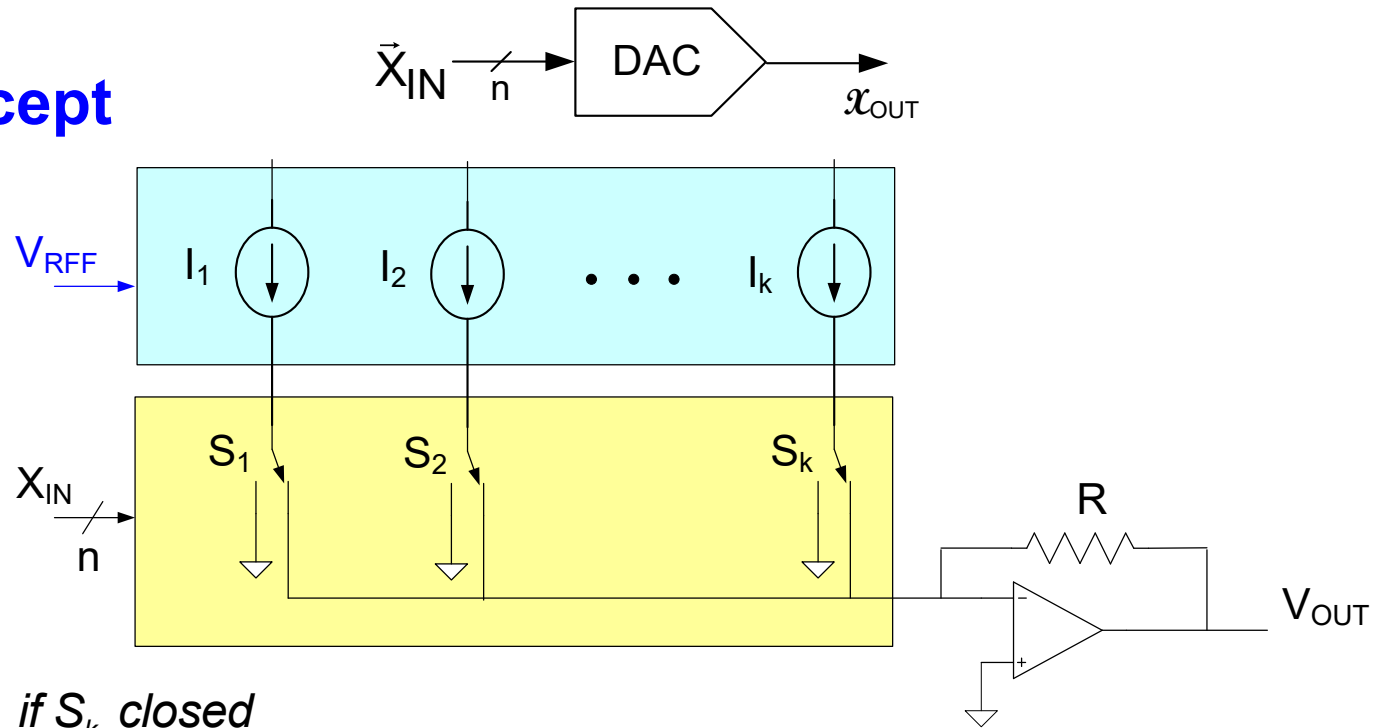
# EE 505

## Lecture 16

### Current Steering DACs

# Current Steering DACs

## Concept

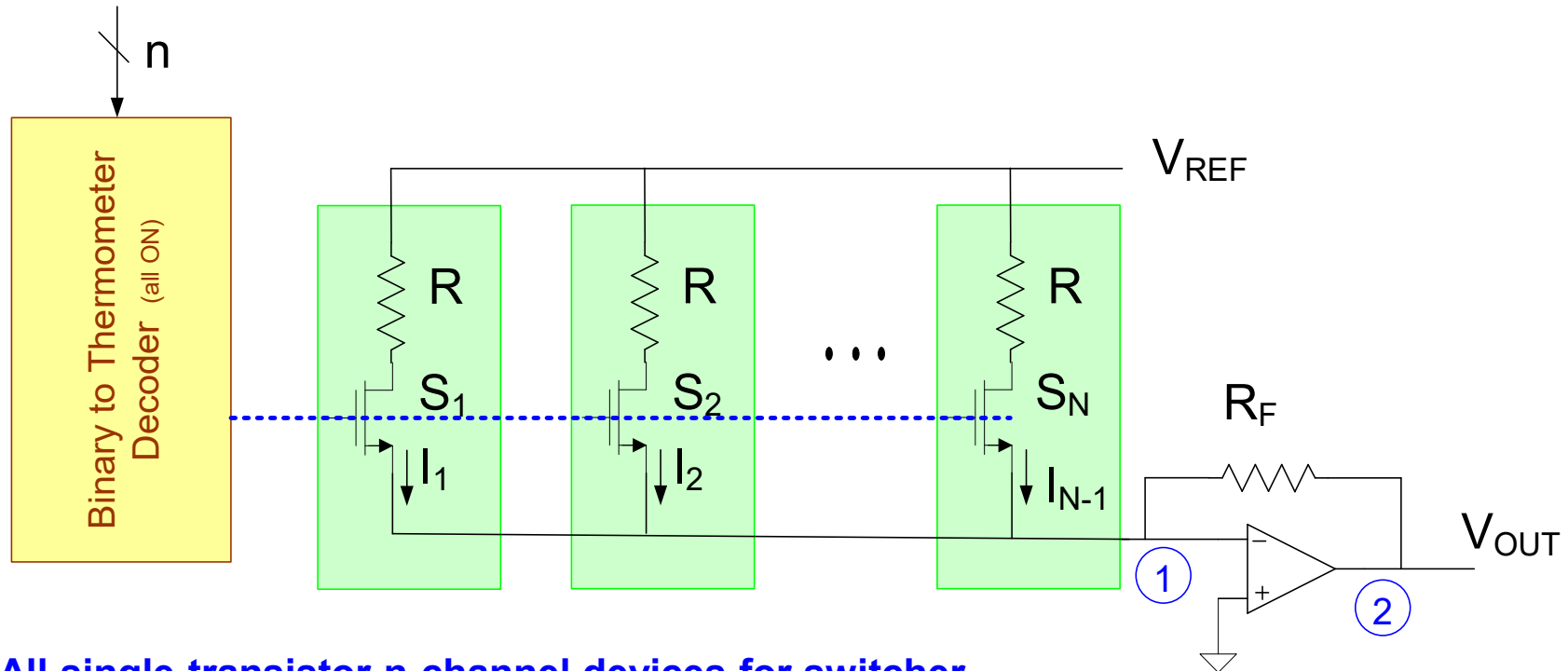


$$d_k = \begin{cases} 1 & \text{if } S_k \text{ closed} \\ 0 & \text{if } S_k \text{ open} \end{cases}$$

$$V_{OUT} = \left[ \sum_{i=1}^k d_i I_i \right] (-R)$$

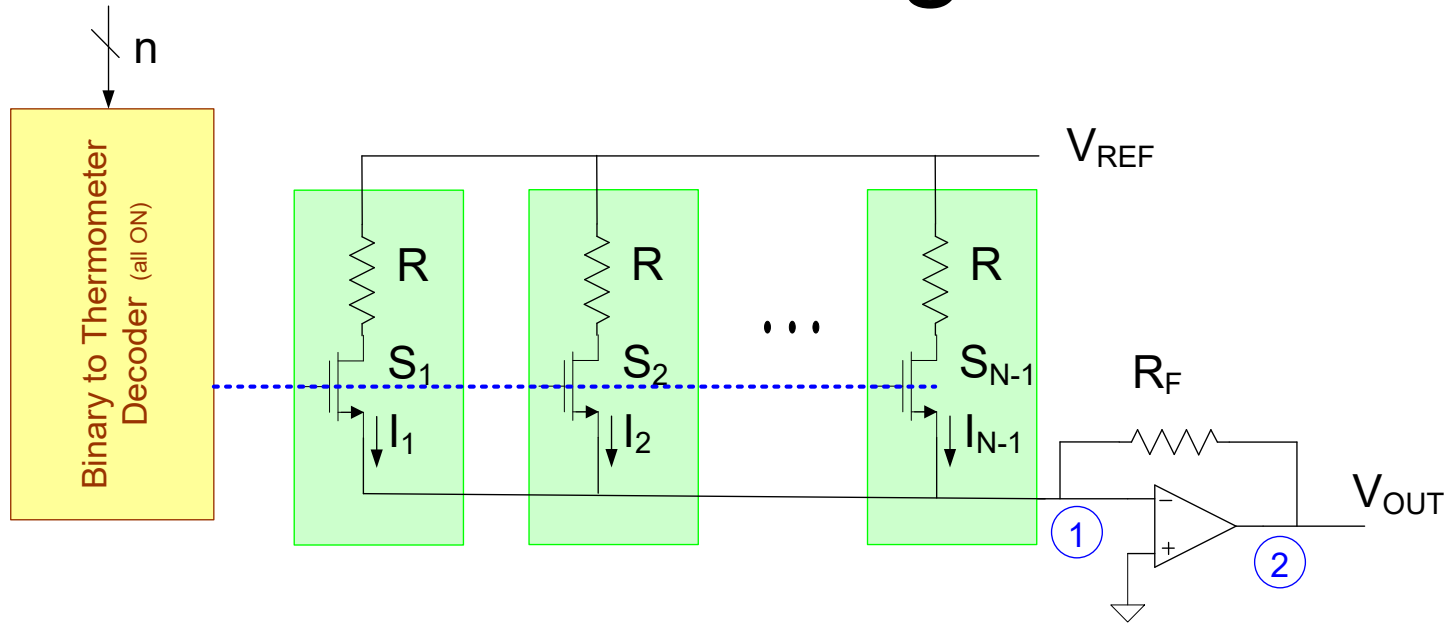
- Current sources usually unary or binary-bundled unary
- Termed bottom-plate switching
- Can eliminate resistors from DAC core
- Op Amp and resistor R can be external
- Can use all same type of switches
- Switch impedance not critical nor is switch matching
- Popular MDAC approach

# Current Steering DACs



- All single-transistor n-channel devices for switcher
- Unary  $R$ :switch cells
- Parasitic capacitances on drain nodes of switches cause transient settling delays
- $R+R_{sw}$  is nonlinear (so nonlinear relationship between  $I_k$  and  $V_{REF}$ ) but does not affect linearity of DAC
- Resistor and switch impedance matching important
- Previous code dependent transient (parasitic capacitances on drains of switches)

# Current Steering DACs



## Transistor Implementation of Switches

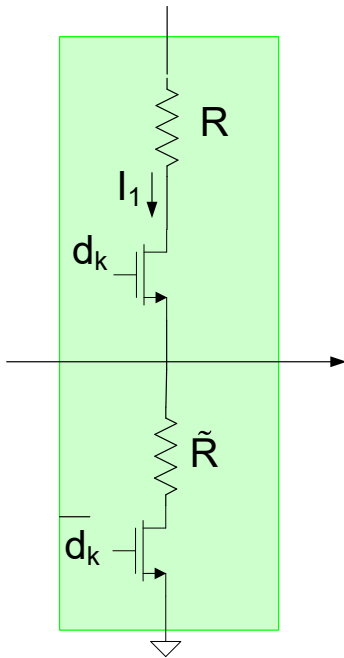
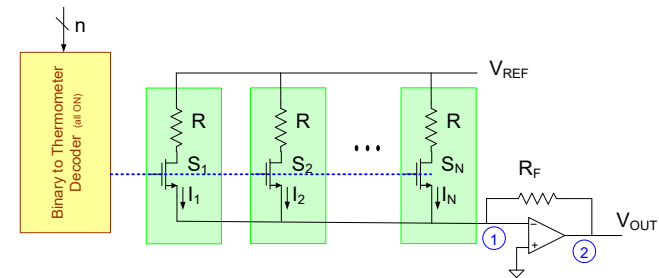
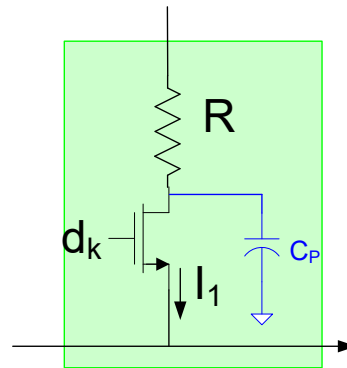
$$\beta = \frac{\frac{R_{CELL}}{k}}{\frac{R_{CELL}}{k} + R_F} = \frac{R_{CELL}}{R_{CELL} + kR_F}$$

$$\text{If } V_{OUTFS} = -V_{REF} \frac{N-1}{N} \quad R_{CELL} = \frac{(N-1)^2}{N} R_F$$

$$\frac{N-1}{2N-1} < \beta \leq 1 \quad \xrightarrow{\text{approximately}} \quad 0.5 < \beta \leq 1$$

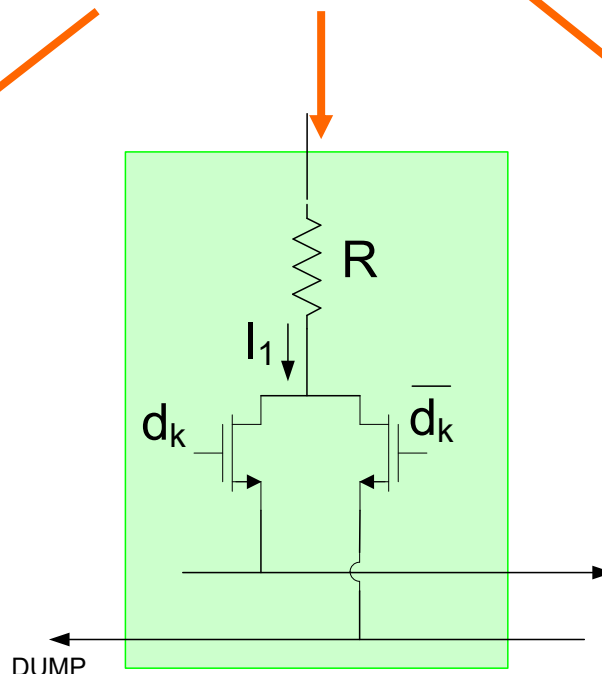
Phase-margin code dependent so distortion will be introduced if not fully settled  
 Current drawn from  $V_{REF}$  changes with code (settling issues if  $R_{0\_VREF}$  is not 0)

# Current Steering DACs



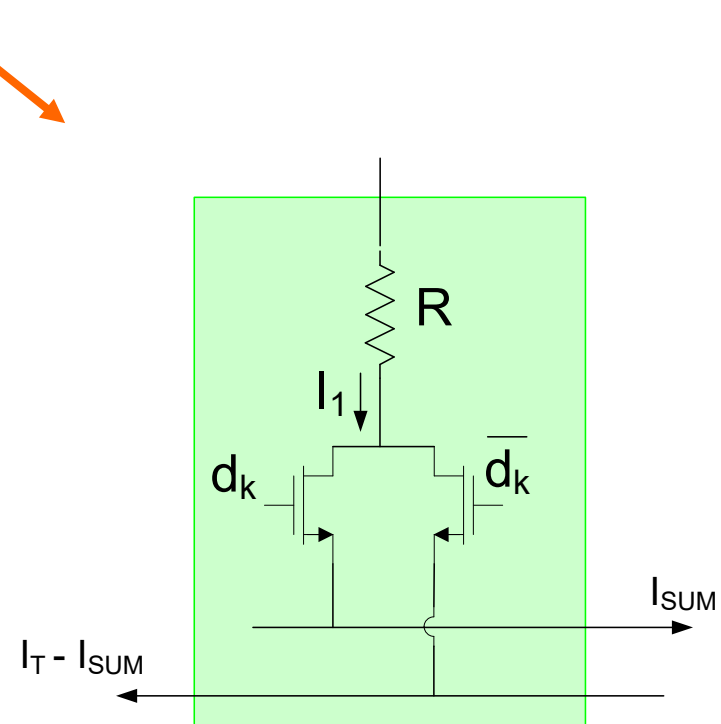
$\beta$  Compensation

(Actually static  $\beta$  comp)  
(keeps  $\beta$  at approximately  $\frac{1}{2}$  for all codes,  
reduces size of compensation capacitor))



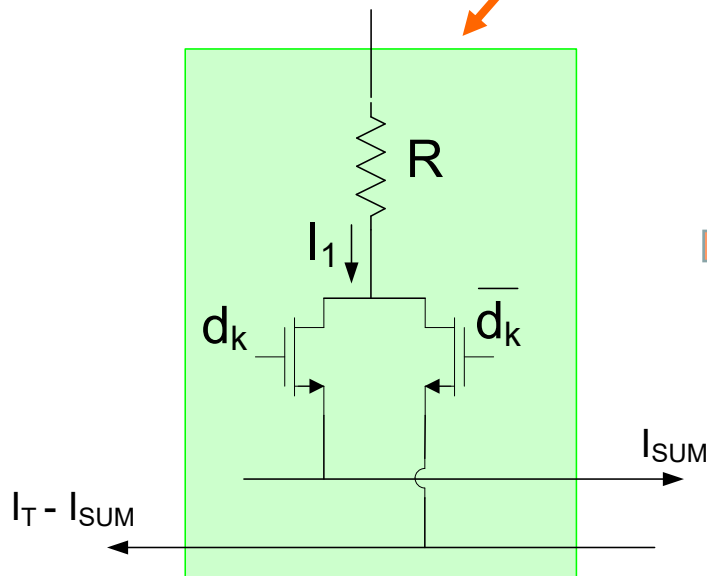
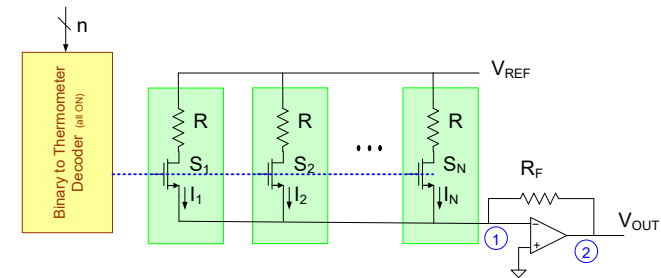
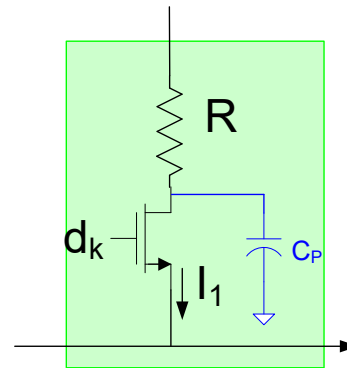
$C_P$  Compensation

(to keep  $C_P$  from charging to  $V_{REF}$  when off)



Differential Output  
(inherent  $C_P$  compensation)

# Current Steering DACs

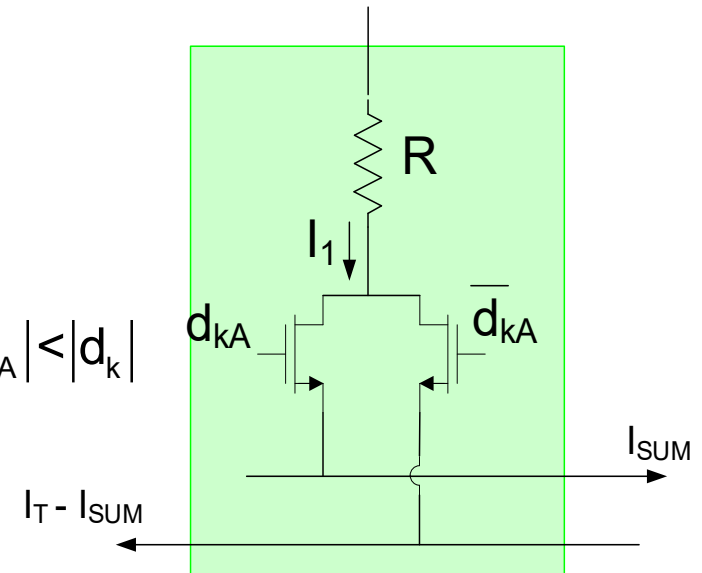


Differential Output

(inherent  $C_P$  compensation)



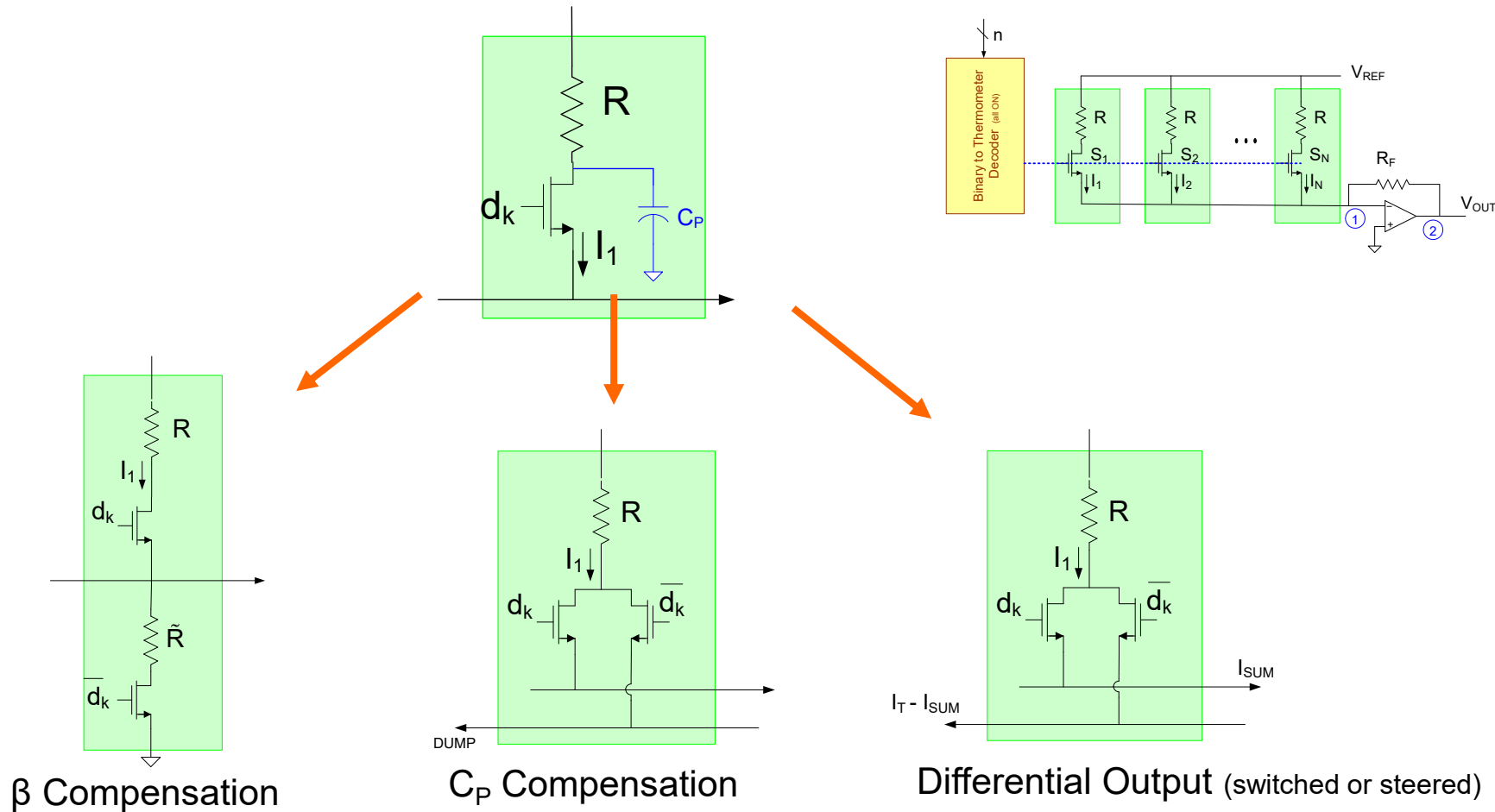
$$|d_{kA}| < |d_k|$$



Differential Output

- Steer current rather than switch current
- Signal swing needs to be just large enough to move current from left side to right side

# Current Steering DACs



Will  $\beta$  compensation “half” resistance of cells?

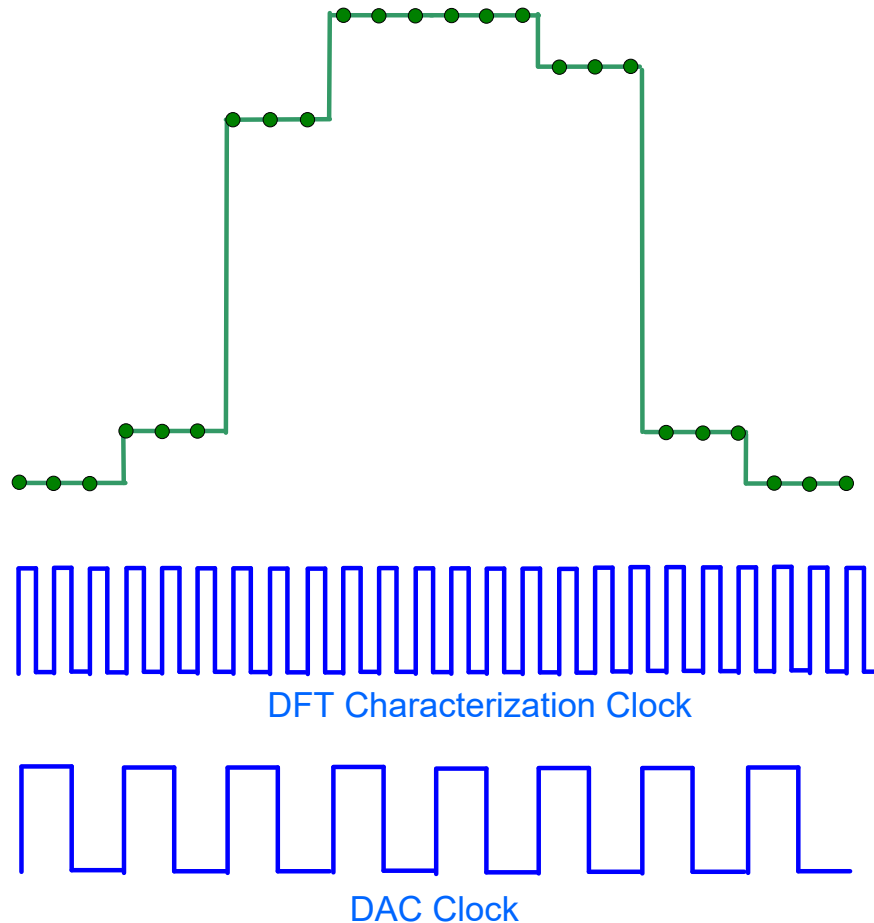
Will  $\beta$  compensation double area for cells?

Is matching of  $R$  and compensating  $R$  critical?

Can  $C_P$  and  $\beta$  compensation be used simultaneously?

Is the frequency-dependent  $\beta$  code dependent?

# Spectral Characterization of DACs (a measure of linearity)

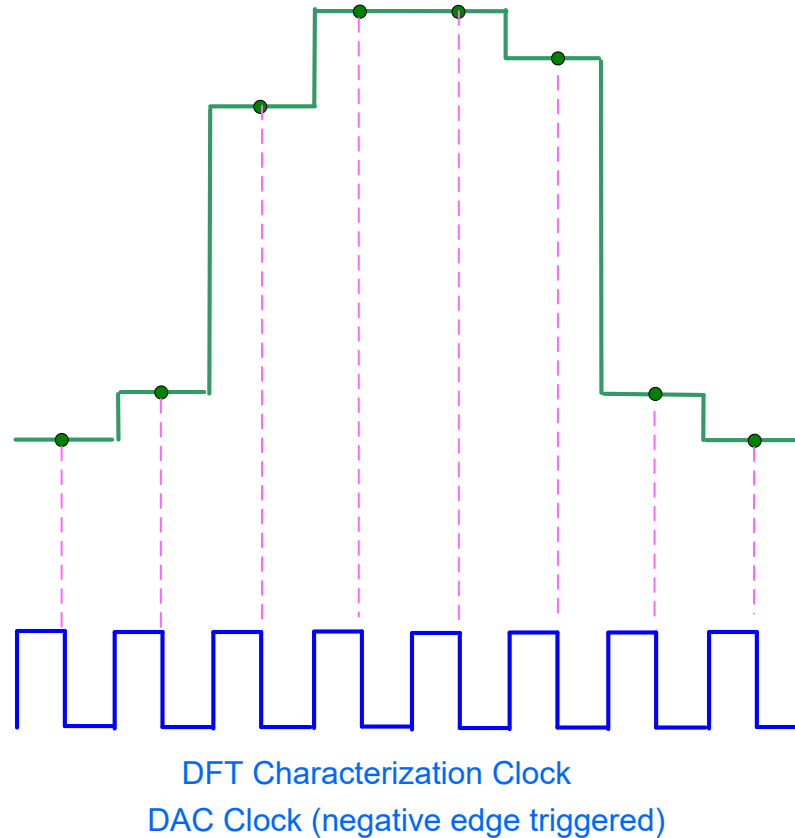


many more samples per DAC clock are often used  
(e.g. 64K samples, 31 periods would be approx 2114 samples/period)

Is this how we should characterize the spectral performance of a DAC?



# Spectral Characterization of DACs (a measure of linearity)

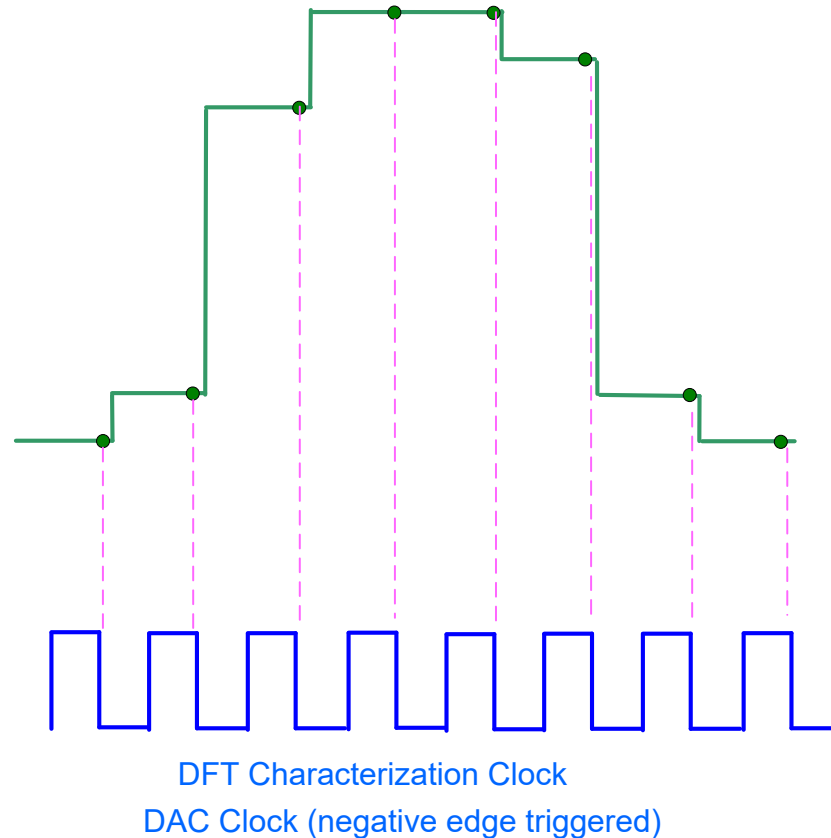


one mid-period sample per DAC clock period (or maybe even less)

Assume Nyquist sampling rate is satisfied

Is this how we should characterize the spectral performance of a DAC?

# Spectral Characterization of DACs (a measure of linearity)

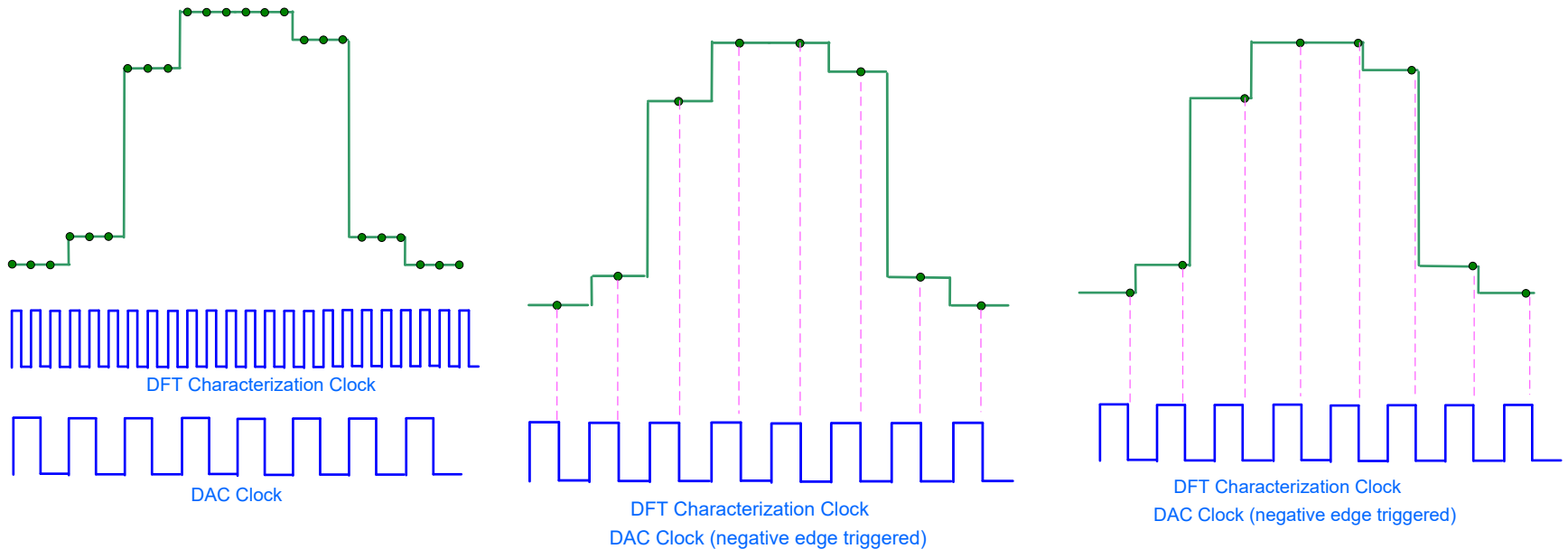


one near-end sample per DAC clock period

Assume Nyquist sampling rate is satisfied

Is this how we should characterize the spectral performance of a DAC?

# Spectral Characterization of DACs (a measure of linearity)



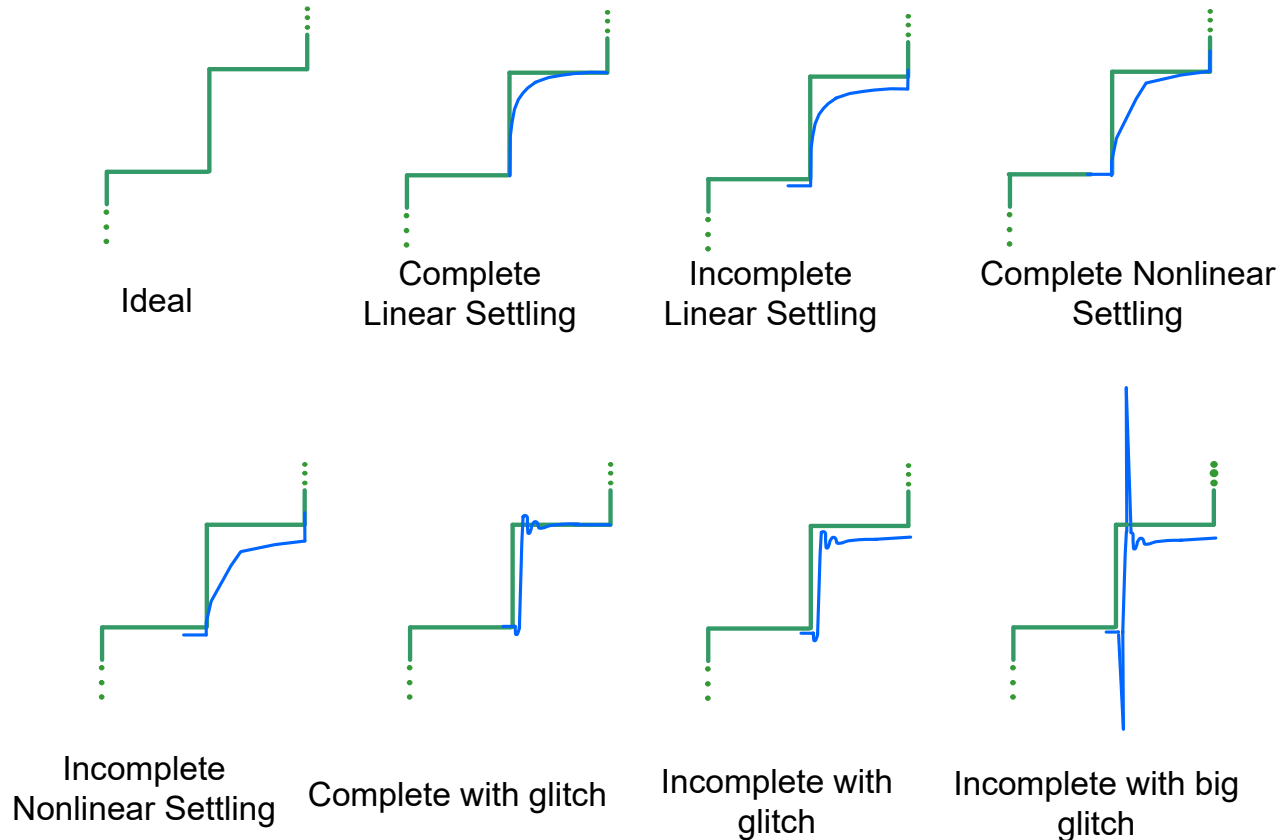
Assume Nyquist sampling rate is satisfied

Does it make a difference?

Yes ! But depends on application which is useful

# Spectral Characterization of DACs (a measure of linearity)

Does it make a difference?

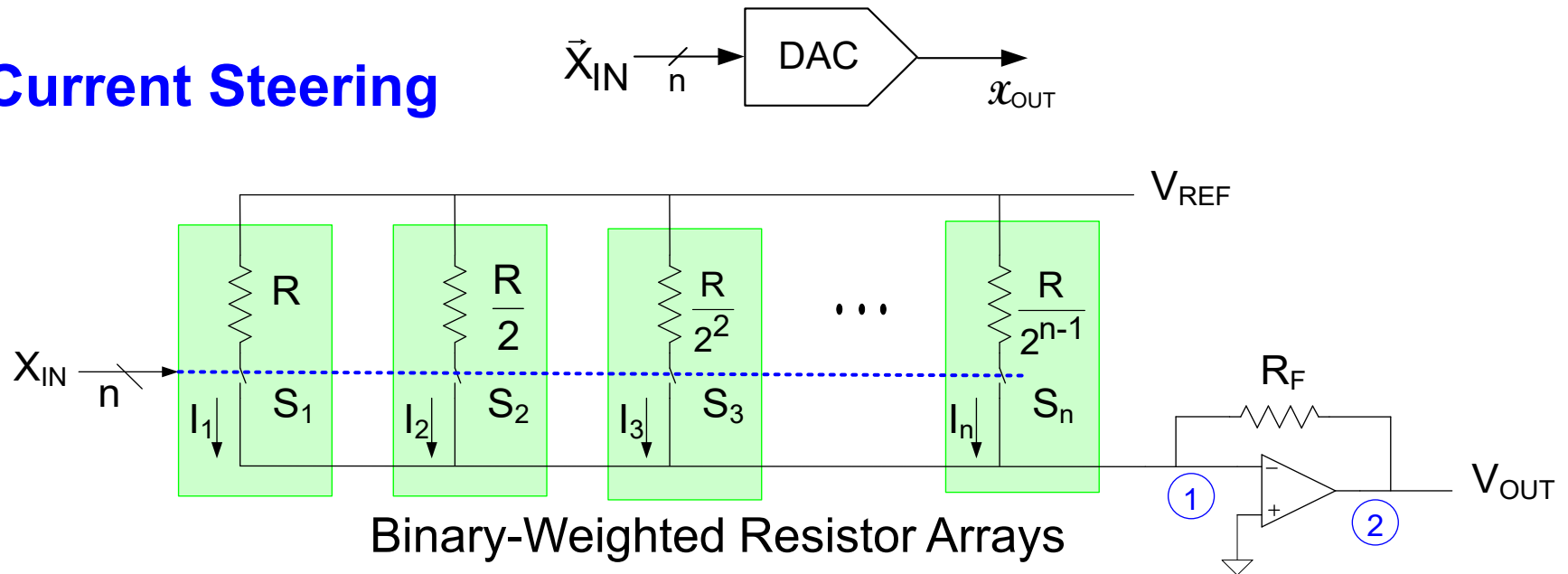


Yes ! But depends on application which is useful

- If entire DAC output is of interest, any nonlinearity including previous code dependence will degrade linearity
- If DAC output is simply sampled, only value at sample point is of concern

# Current Steering DACs

## Current Steering



- Unary cells bundled to implement binary cells (so no net change in number of cells)
- Need for decoder eliminated !
- DNL may be a major problem
- INL performance about same as thermometer coded if same unit resistors used
- Sizing and layout of switches is critical
- Large total resistance

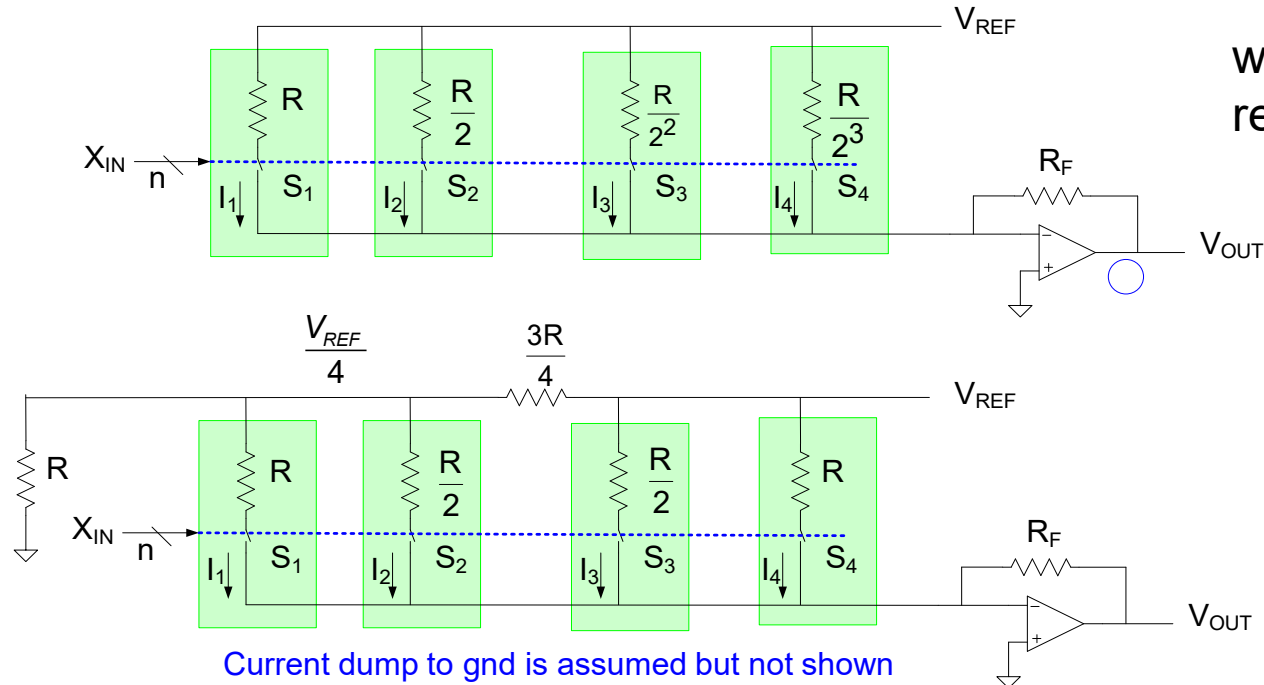
Observe thermometer coding and binary weighted both offer some major advantages and some major limitations

Large DNL dominantly occurs at mid-code and due to ALL resistors switching together  
Can unary cell bundling be regrouped to reduce DNL

# Current Steering DACs

## Reduced Resistance Structure

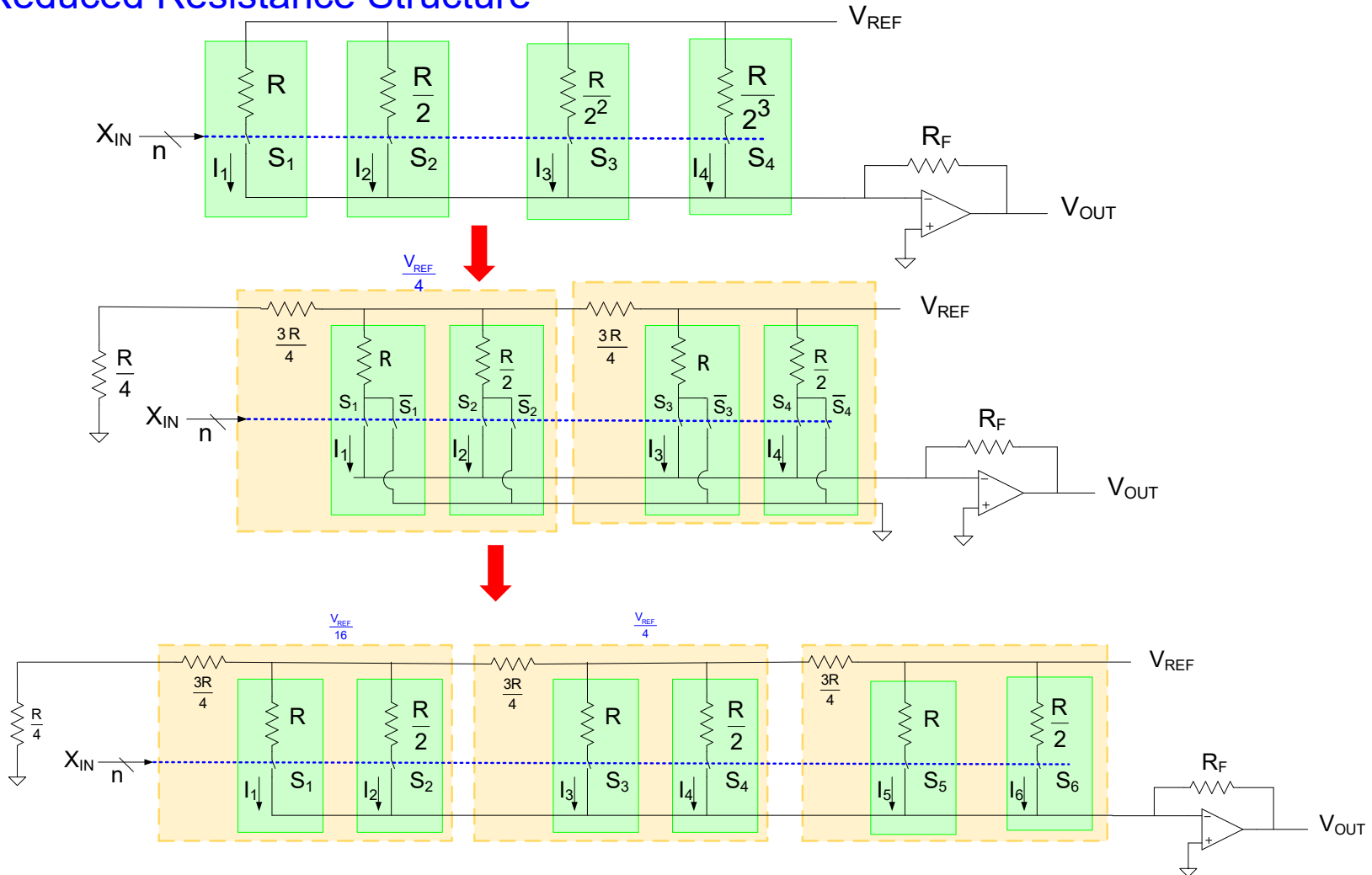
(actually concerned about number of unary cells, not total ohmic resistance)



- Significant reduction in resistance possible
- Can be inserted at more than one place to further reduce resistance values
- Introduces a “floating node” but voltage on floating node does not change (if current is steered)
- Current drawn from  $V_{REF}$  does not change with code
- Dummy switching can be used for  $\beta$  compensation
- If inserted at each intersection becomes R-2R structure

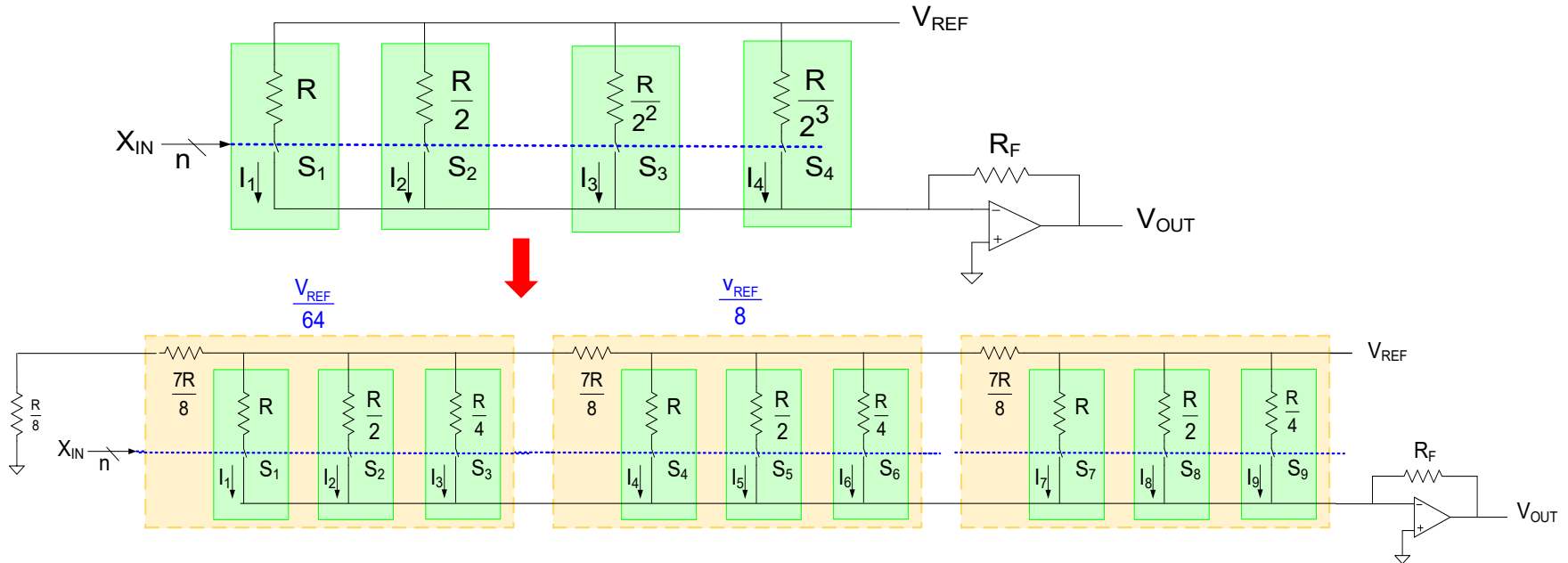
# Current Steering DACs

## Reduced Resistance Structure

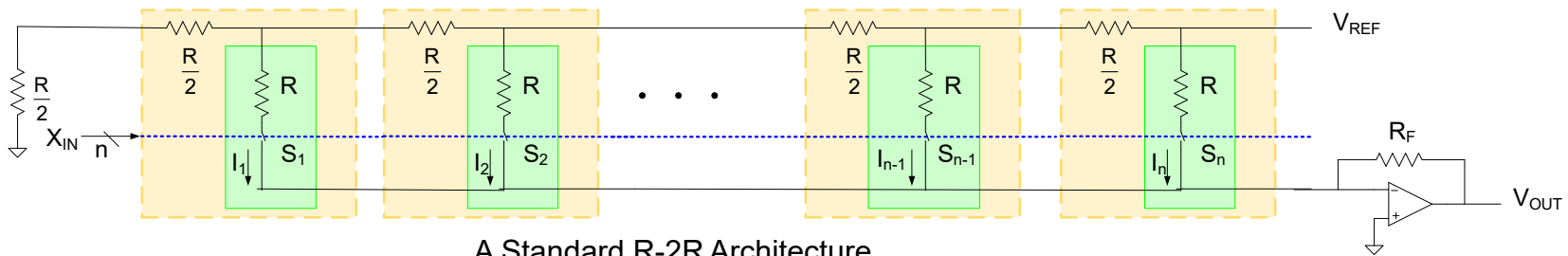


# Current Steering DACs

## Reduced Resistance Structure



OR



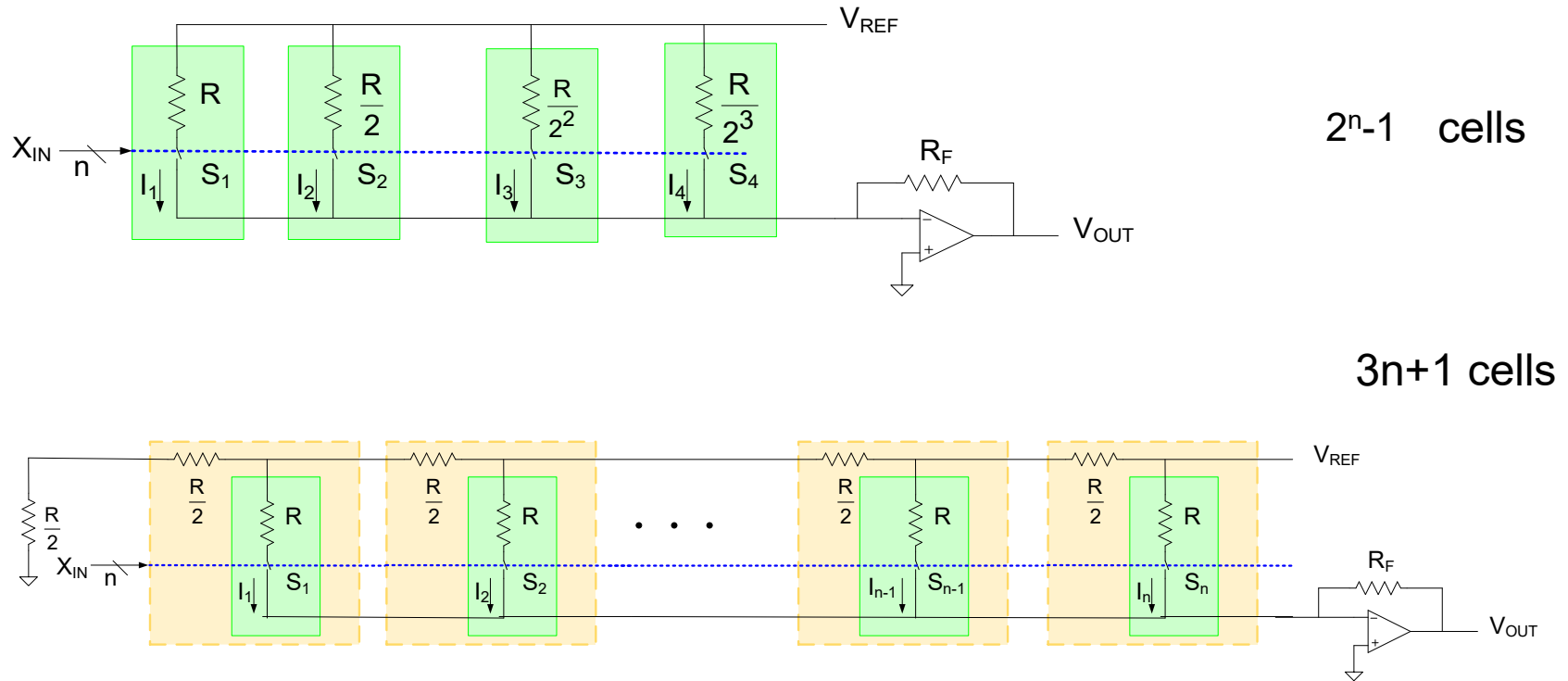
A Standard R-2R Architecture

with unary  $R/2$  cells, required  $3n+1$  cells compared to  $2^n-1$  cells for binary bundled array



# Current Steering DACs

## Reduced Resistance Structure



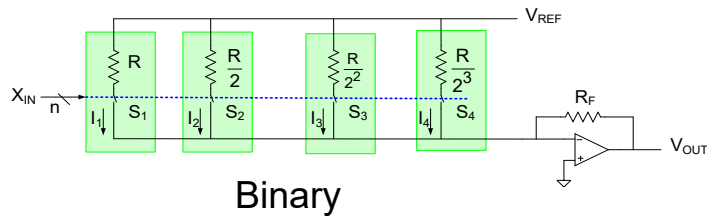
Is the R-2R structure smaller ?

Does the R-2R structure perform better?

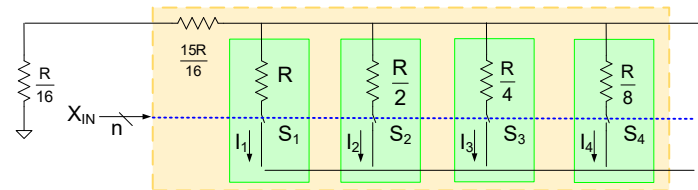
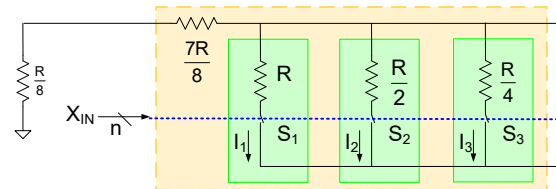
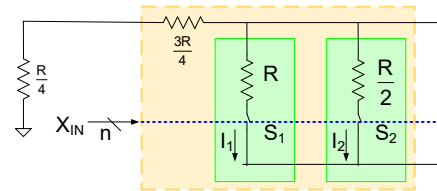
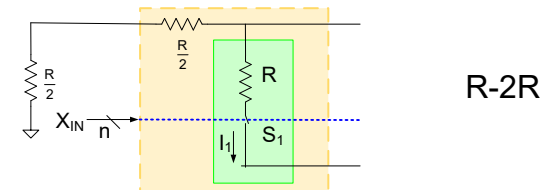
What metric should be used for comparing performance?

# Current Steering DACs

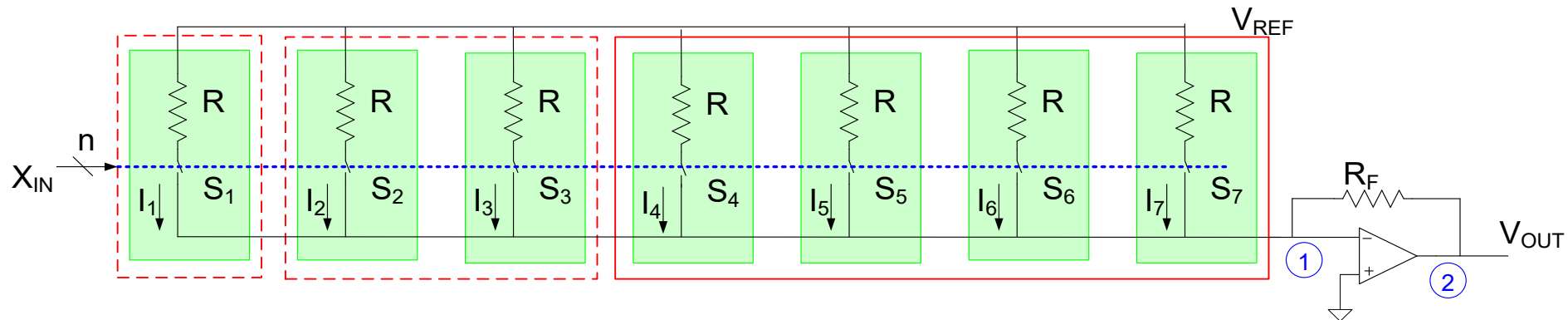
## Reduced Resistance Structure



## Slice Grouping Options with Series Resistors



# Current Steering DACs



Binary-Weighted Resistor Arrays

Actual layout of resistors is very important

# Performance of Thermometer Coded vs Binary Coded DACs

## Conventional Wisdom:

- Thermometer-coded structures have inherently small DNL
- Binary coded structures can have large DNL
- INL of both structures is comparable for same total area (provided area appropriately allocated)

# Comparison of Thermometer Coded and Binary Coded DACs

- Will consider String DAC but nearly same results for current-steering DACs
- Current Steering DAC will generate current from resistors
- For Binary Coded DAC, MSB:  $2^{n-1}$  unary cells in parallel .... LSB: single unary cell

- Consider unit resistor of area  $2\mu\text{m}^2$  (shape not critical)
- Matching parameter  $A_R=0.02\mu\text{m}$
- $R_N=1\text{K}$  (not critical)

$$\sigma_R = \frac{R_N}{\sqrt{A}} A_{pR}$$

- Assume Gaussian Distribution of Resistors

# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

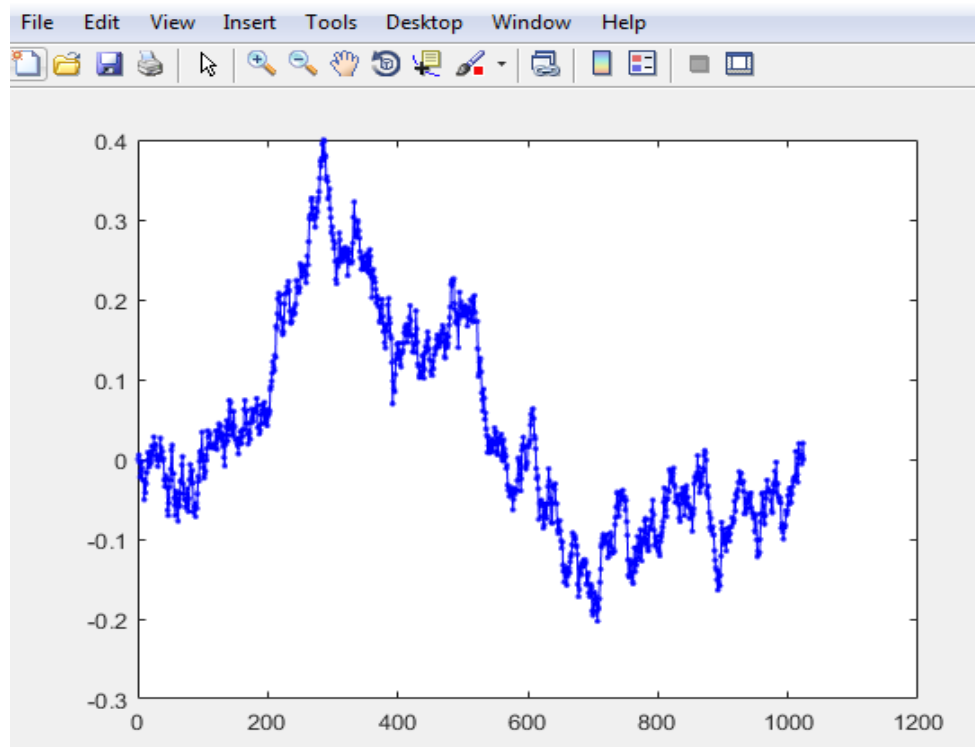
String DAC



$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Resistor Sigma=  $14.14\ \Omega$

Simulation 1:  $\text{INL}_k$



# Comparison of Thermometer Coded and Binary Coded DACs

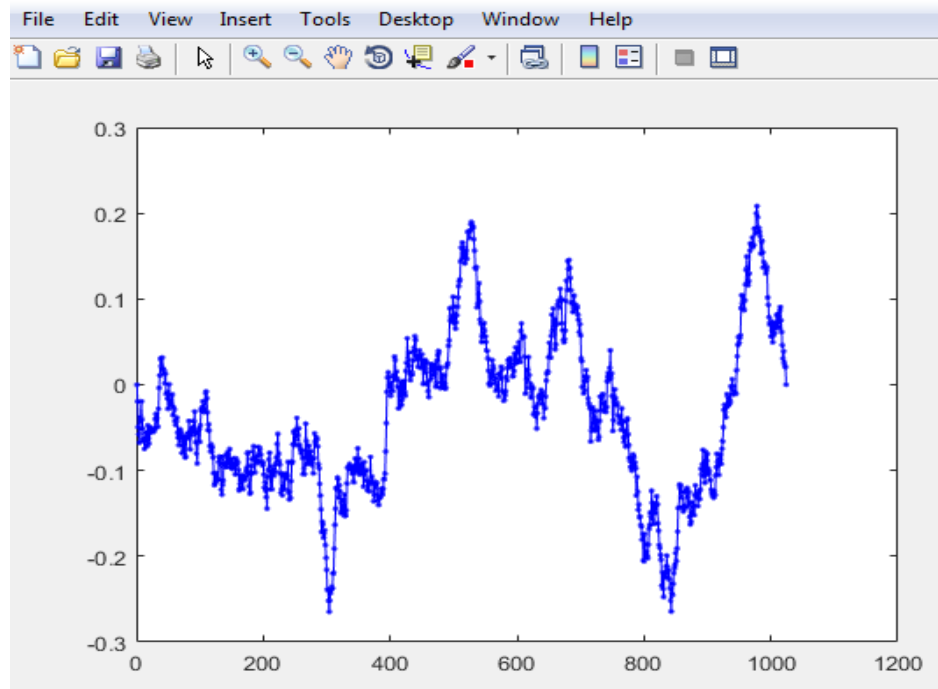
Example:  $n=10$   
String DAC



Resistor Sigma=  $14.14 \Omega$

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Simulation 2:  $\text{INL}_k$



# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

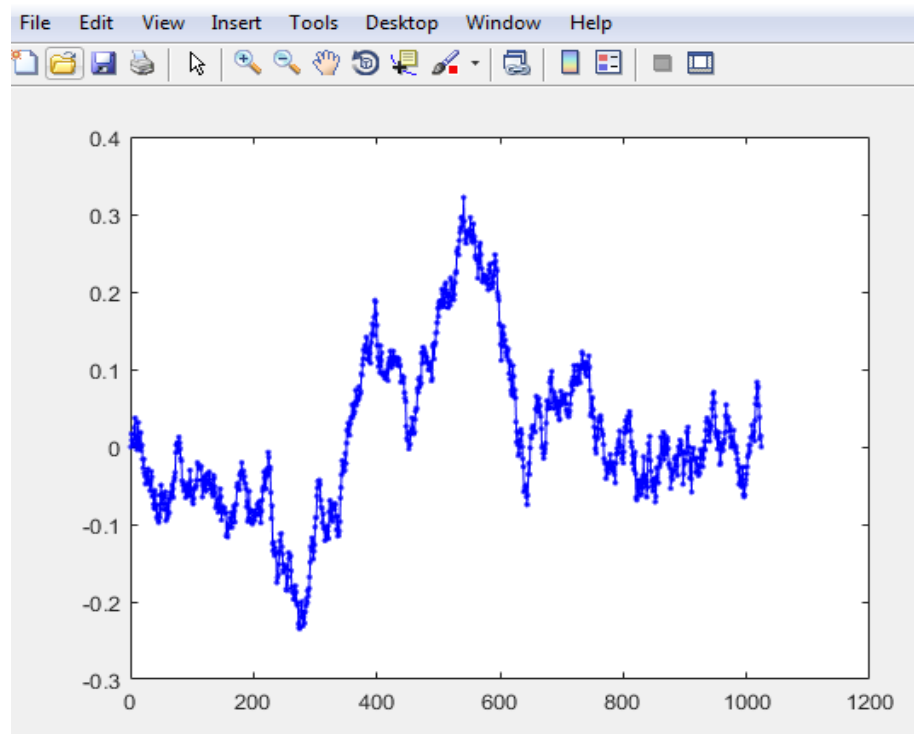
String DAC



$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Resistor Sigma=  $14.14\ \Omega$

Simulation 3:  $\text{INL}_k$





# Comparison of Thermometer Coded and Binary Coded DACs

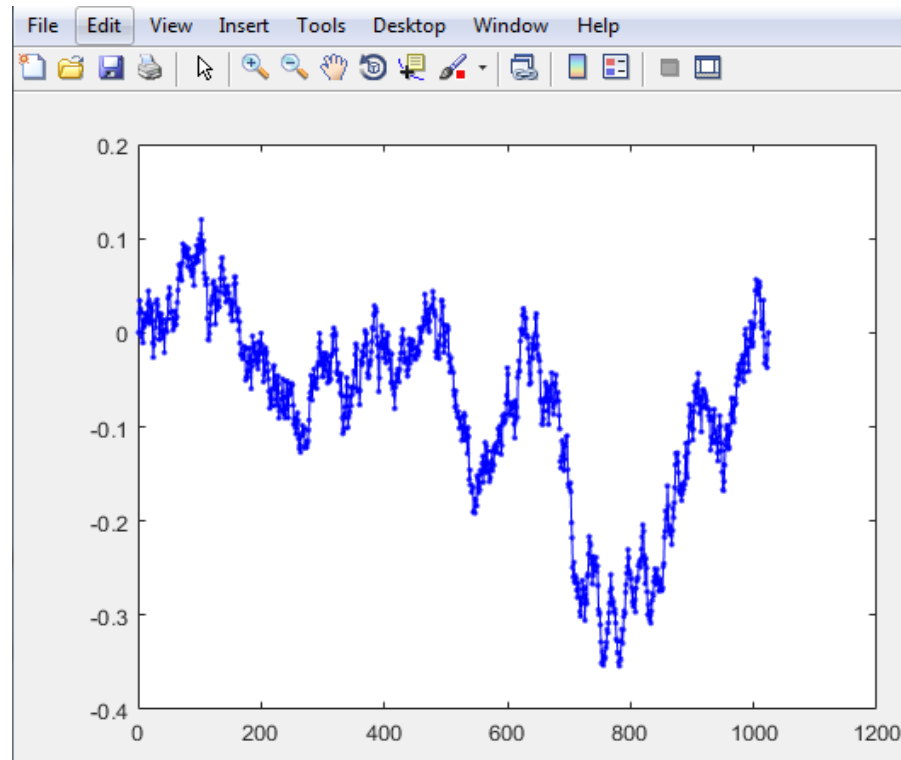
Example:  $n=10$   
String DAC



$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Resistor Sigma=  $14.14\ \Omega$

Simulation 4:  $\text{INL}_k$



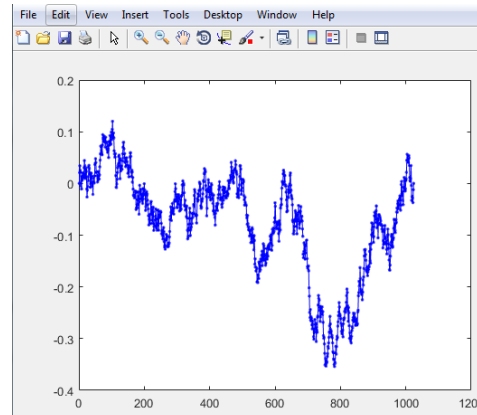
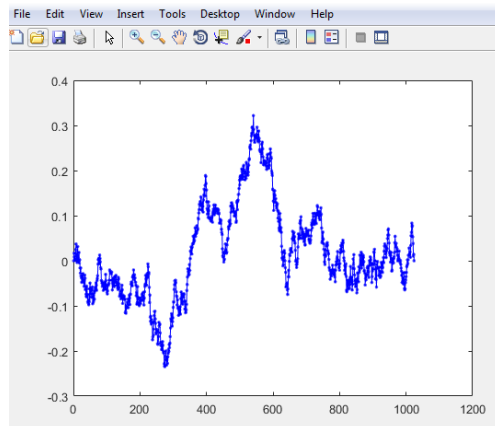
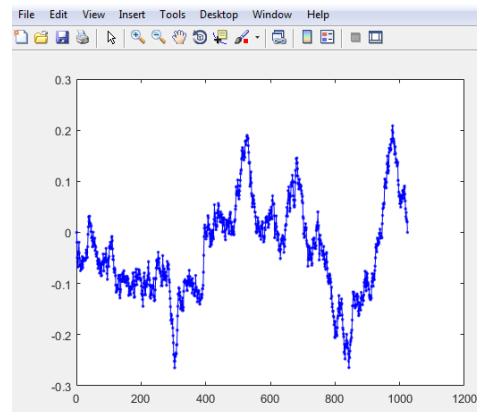
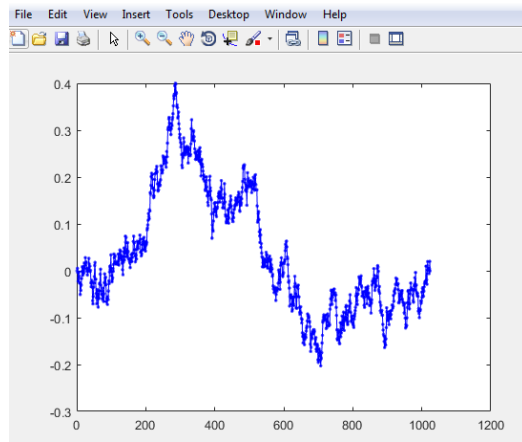
# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$   
String DAC

$$A_R = 0.02 \mu\text{m}$$
$$R_N = 1\text{K}$$



Resistor Sigma =  $14.14 \Omega$



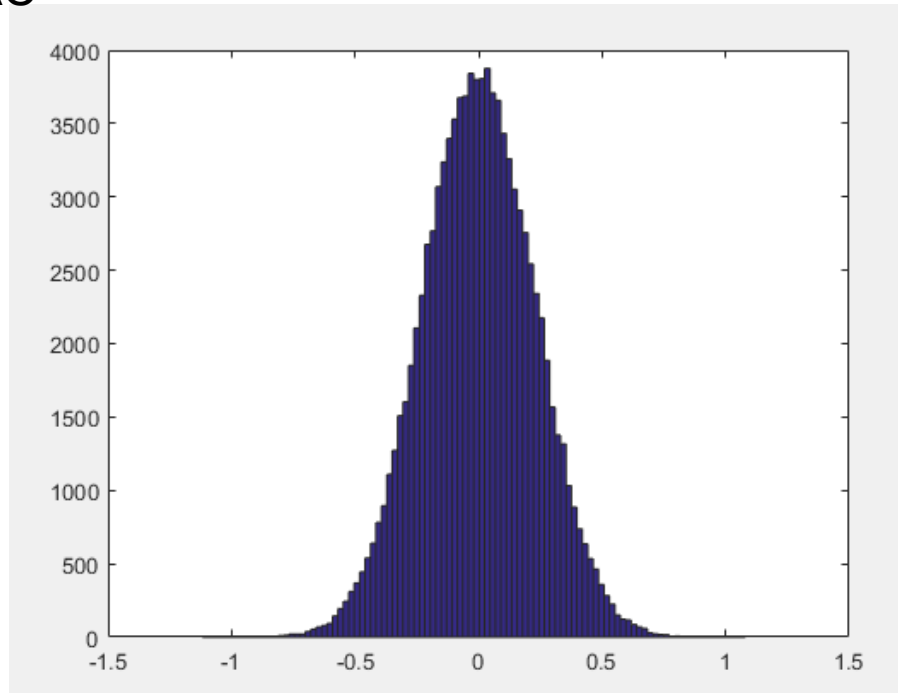
Low DNL and random walk nature should be apparent

# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$   
String DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$   
→

Resistor Sigma =  $14.14\ \Omega$



INLkmax\_mean =  $-2.11116\text{e-}05$

INLkmax\_sigma = 0.226783

Histogram of INL<sub>kmax</sub> from 100,000 runs

Appears to be Gaussian

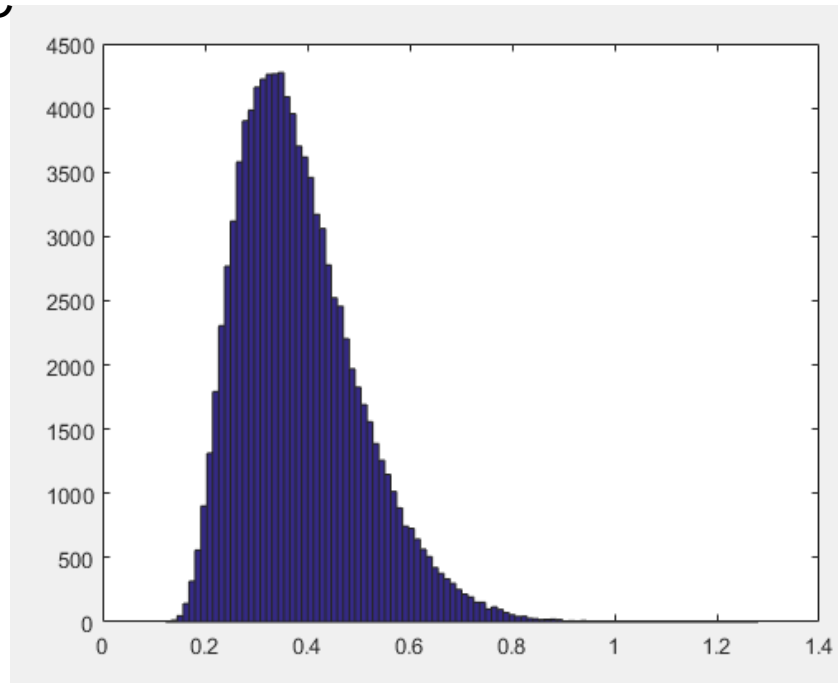
# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$   
String DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Resistor Sigma=  $14.14\ \Omega$



INLmean = 0.384382  
INLsigma = 0.117732

Histogram of INL from 100,000 runs

Not Gaussian

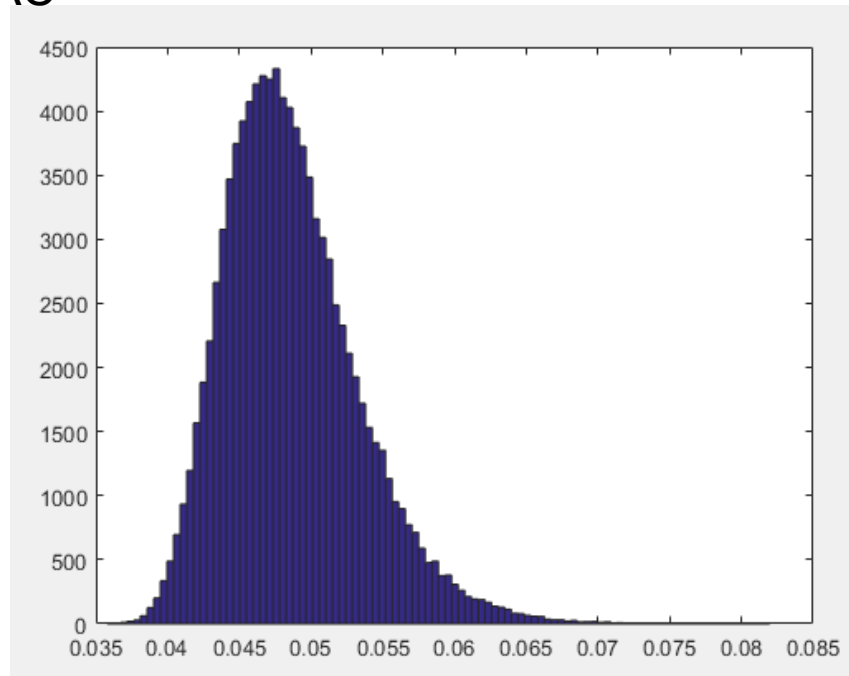
# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$   
String DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Resistor Sigma =  $14.14\ \Omega$



DNLmean = 0.0486494  
DNLsigma = 0.00471025

Histogram of DNL from 100,000 runs

Not Gaussian but both mean and sigma are very small

# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

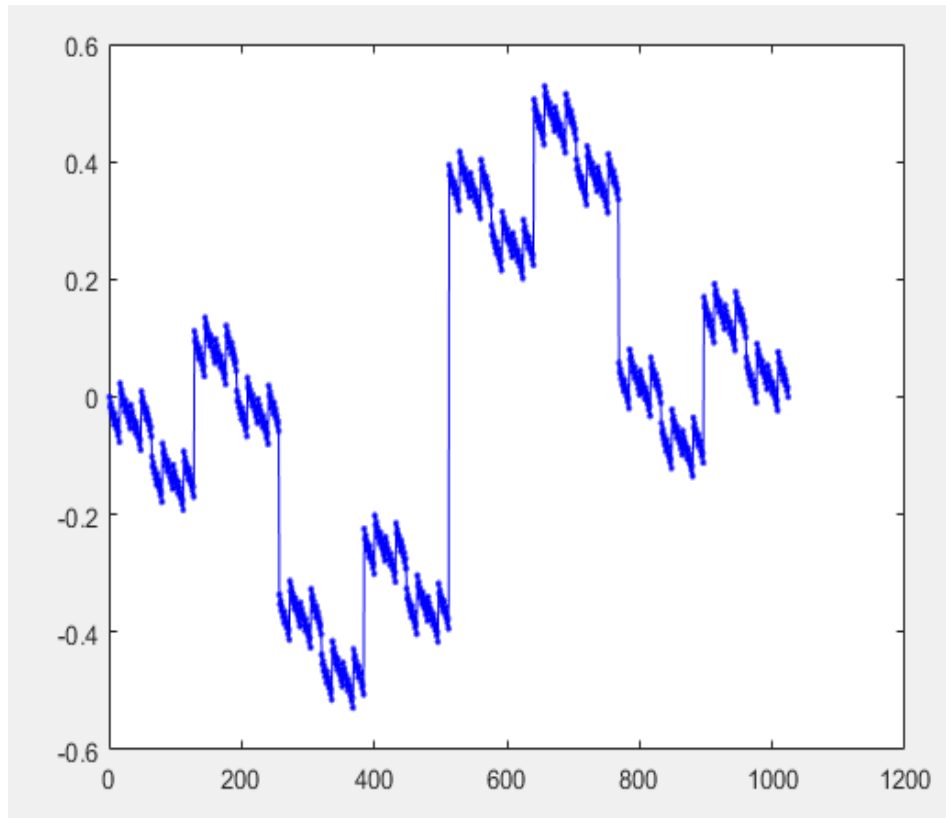


Resistor Sigma= 14.14  $\Omega$

Binary DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Simulation 1:  $\text{INL}_k$



# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

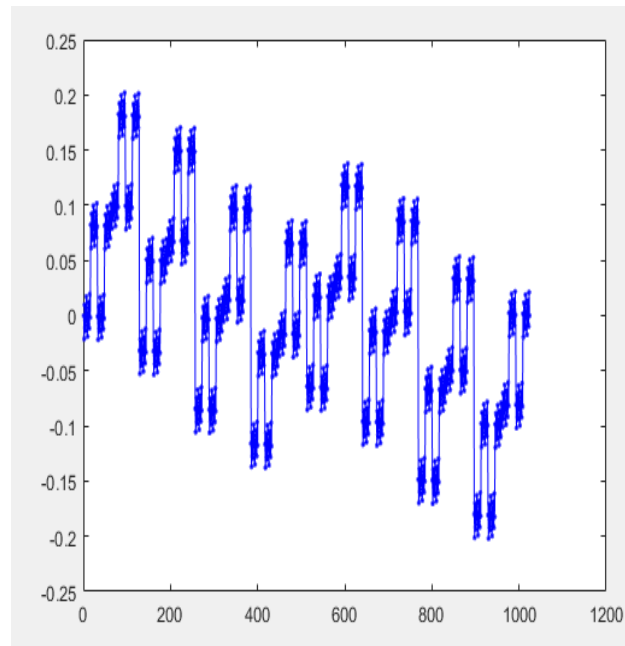
Binary DAC

Simulation 2:  $INL_k$



$A_R=0.02\mu m$   
 $R_N=1K$

Resistor Sigma=  $14.14 \Omega$



# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

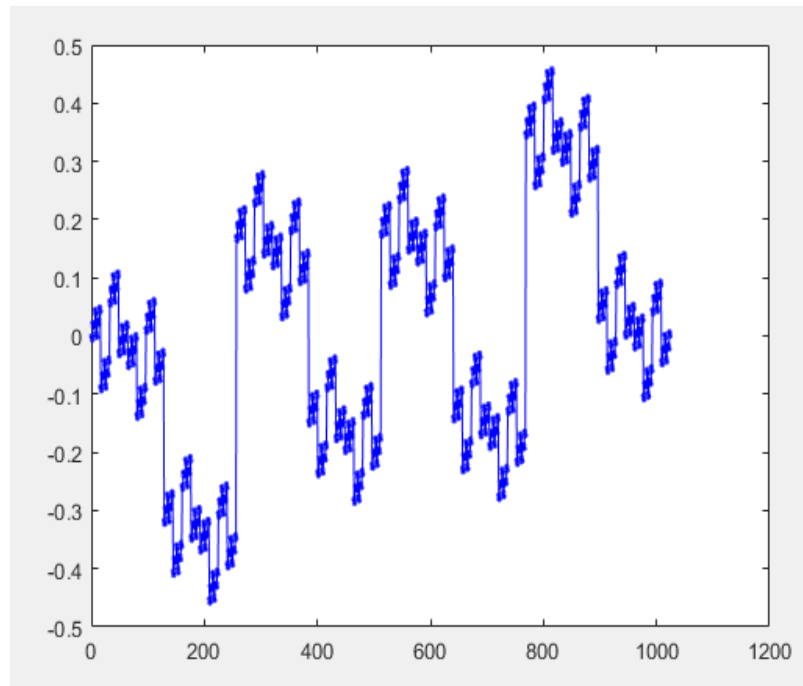


Resistor Sigma= 14.14  $\Omega$

Binary DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Simulation 3:  $\text{INL}_k$





# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

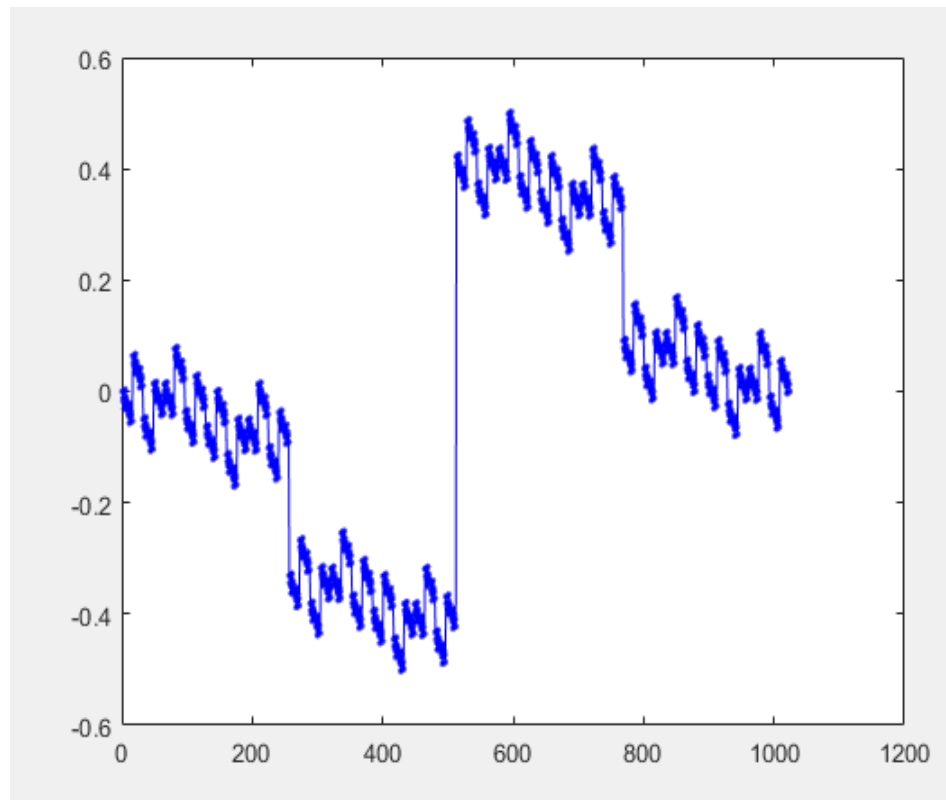


Resistor Sigma= 14.14  $\Omega$

Binary DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Simulation 4:  $\text{INL}_k$



# Comparison of Thermometer Coded and Binary Coded DACs

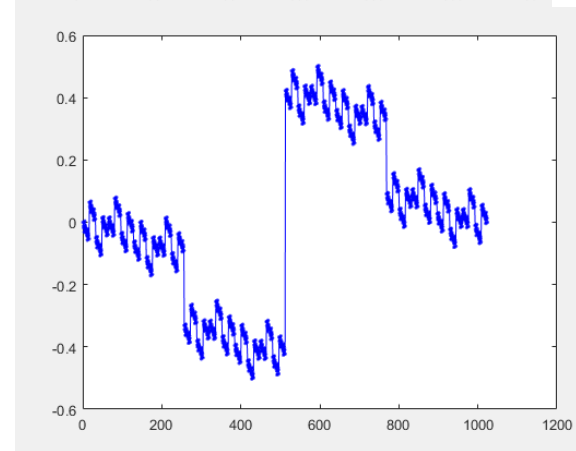
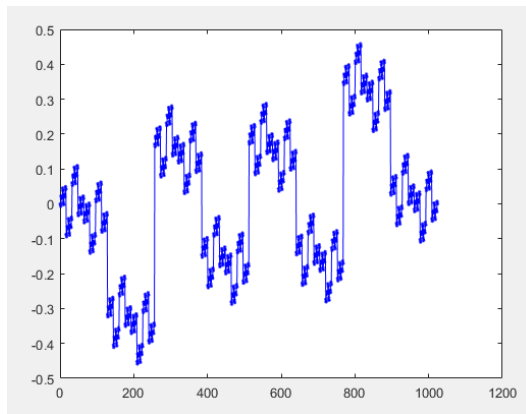
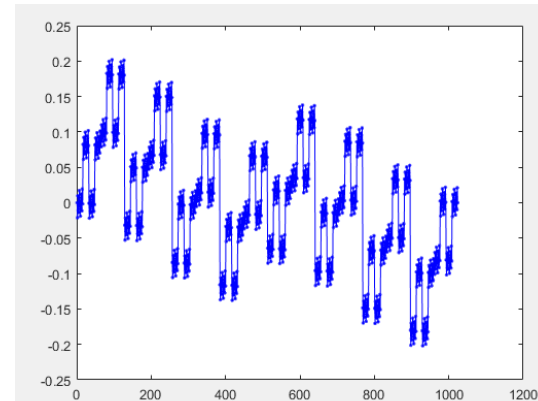
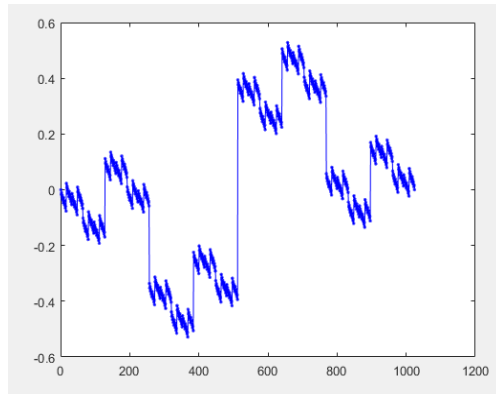
Example:  $n=10$



Resistor Sigma= 14.14  $\Omega$

Binary DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Large DNL bit INL does not appear to be much different than for string DAC

# Comparison of Thermometer Coded and Binary Coded DACs

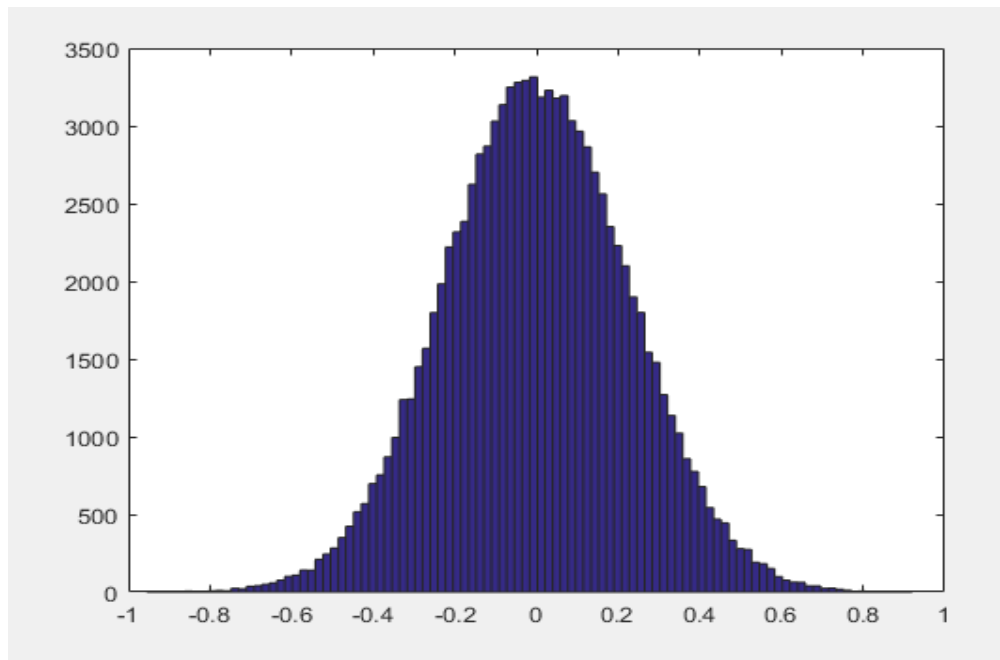
Example:  $n=10$

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Resistor Sigma =  $14.14\ \Omega$

Binary DAC



INLkmax\_mean =  $-.00526008$

INLkmax\_sigma =  $0.23196$

Histogram of  $\text{INL}_{\text{kmax}}$  from 100,000 runs

Appears to be Gaussian

# Comparison of Thermometer Coded and Binary Coded DACs

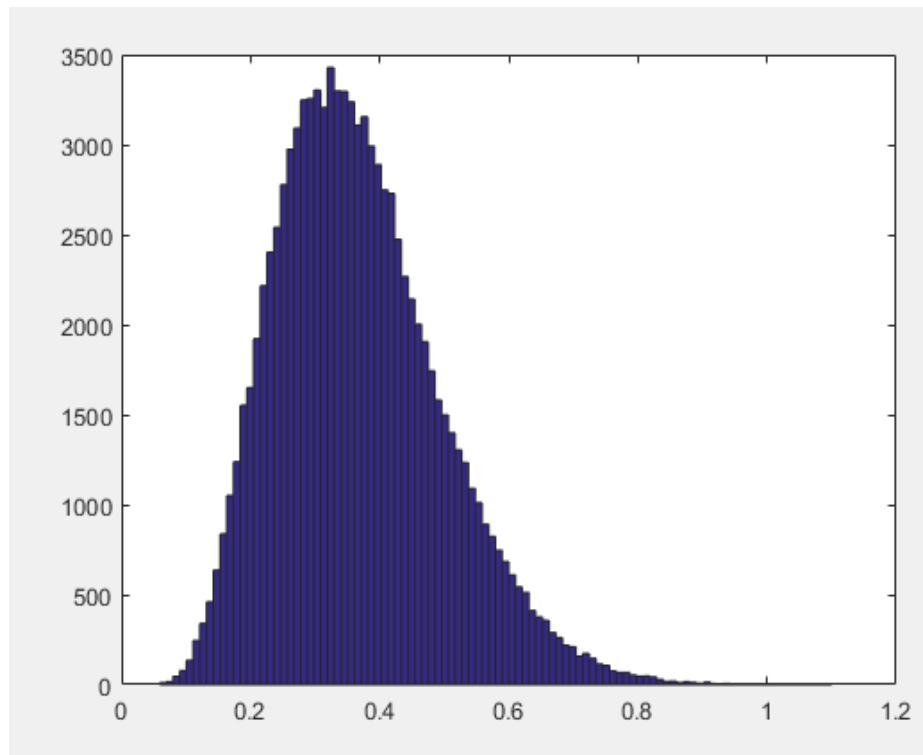
Example:  $n=10$

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Resistor Sigma =  $14.14\ \Omega$

Binary DAC



Histogram of INL from 100,000 runs

Not Gaussian

INLmean = 0.368441  
INLsigma = 0.126133

# Comparison of Thermometer Coded and Binary Coded DACs

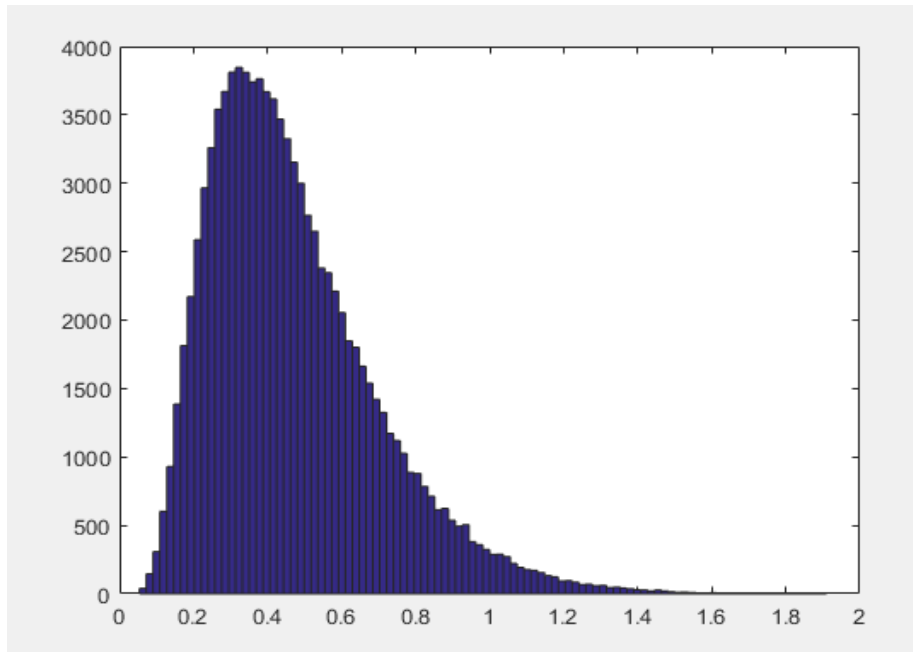
Example:  $n=10$

Binary DAC

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Resistor Sigma=  $14.14\ \Omega$



DNLmean = 0.46978

DNLsigma = 0.227768

Histogram of DNL from 100,000 runs

Not Gaussian and both mean and sigma are not small

# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

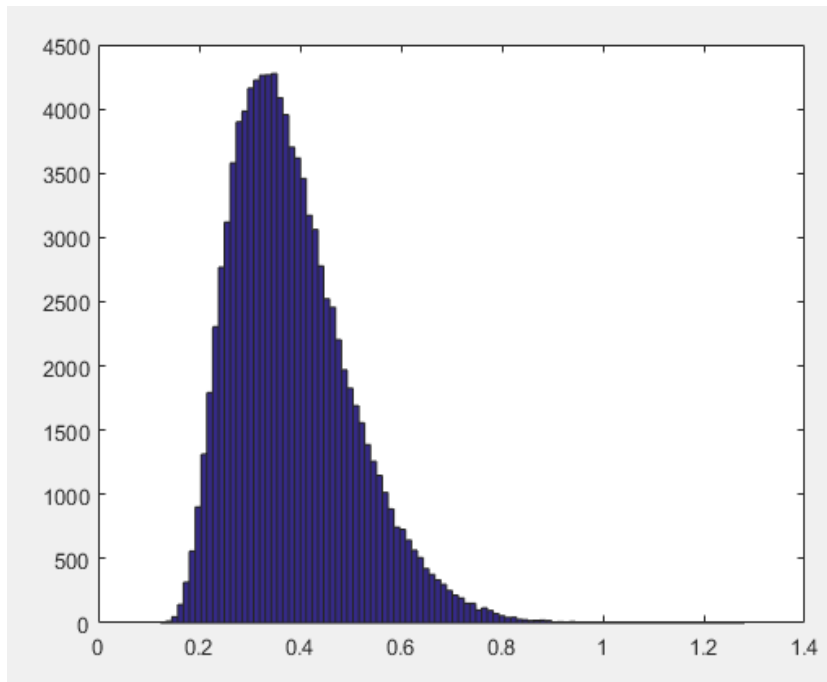
$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



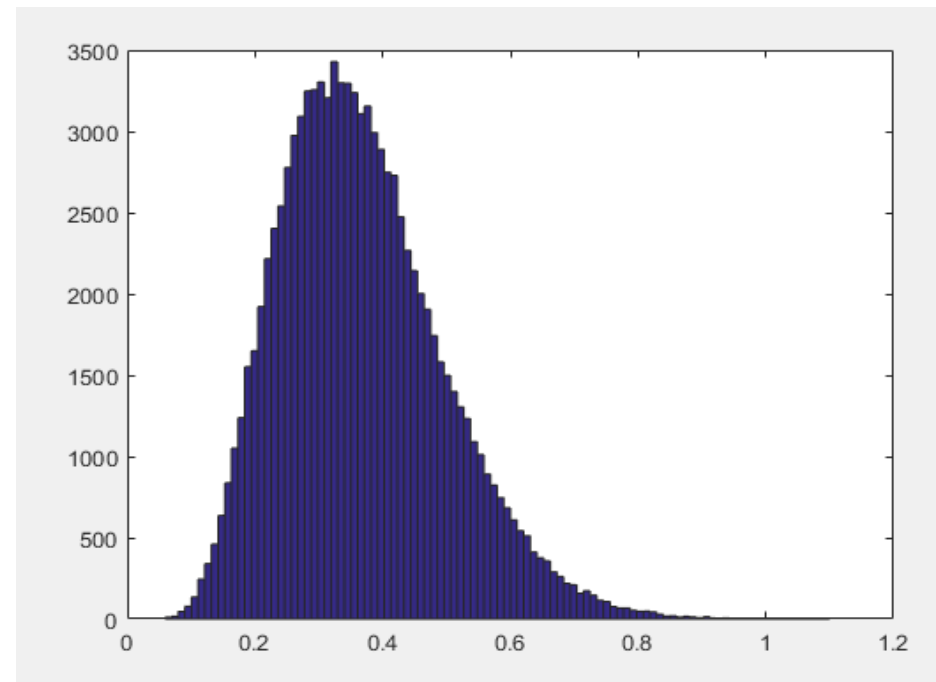
Resistor Sigma=  $14.14\ \Omega$

Both structures have essentially the same area

String DAC



Binary DAC



Histogram of INL from 100,000 runs

Since mathematical form for PDF is not available, not easy to analytically calculate yield

# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$

$A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$



Resistor Sigma=  $14.14\ \Omega$

Both structures have essentially the same area

## String DAC

Resolution = 10       $AR = 0.02$   
Rnom = 1000      Area Unit Resistor =  $2\mu\text{m}^2$   
INLkmax\_mean =  $-2.11116\text{e-}05$   
INLmean = 0.384382  
INLtarget = 0.5000

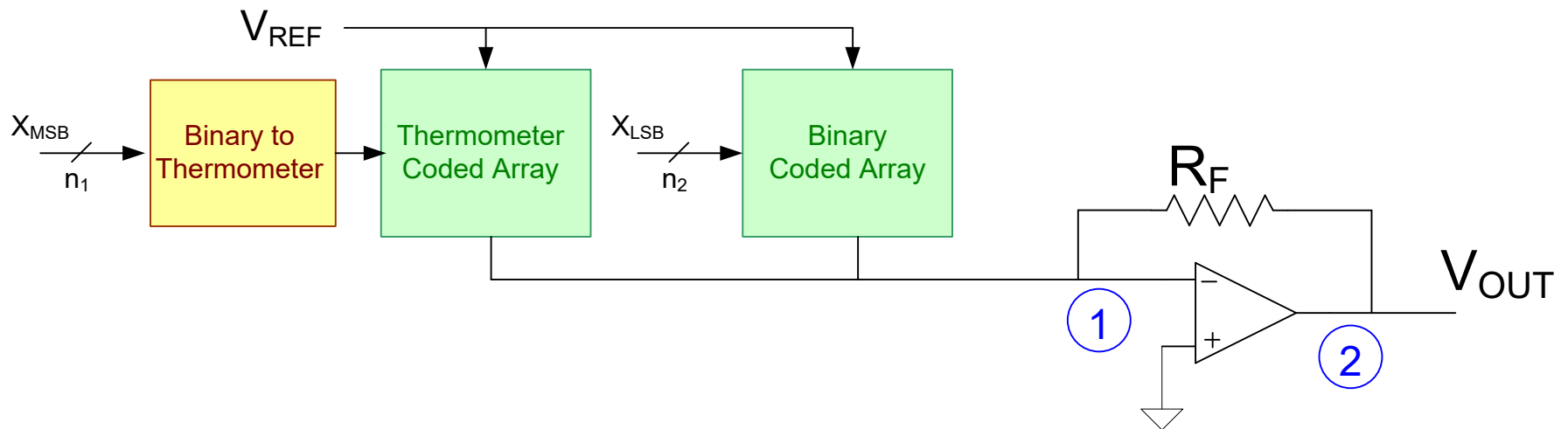
Nruns = 100000  
Resistor Sigma= 14.1421  
INLkmax\_sigma = 0.226783  
INLsigma = 0.117732  
Yield(%) = 84.0120

## Binary DAC

Resolution = 10       $AR = 0.02$   
Rnom = 1000      Area unit resistor= $2\mu\text{m}^2$   
INLmean = 0.367036  
INLkmax\_mean = 0.000130823  
DNLmean = 0.46978  
INLtarget = 0.5000

Nruns = 100,000  
Resistor Sigma= 14.1421  
INLsigma = 0.128294  
INLkmax\_sigma = 0.226276  
DNLsigma = 0.227768  
Yield (%) = 84.8580

# Current Steering DACs



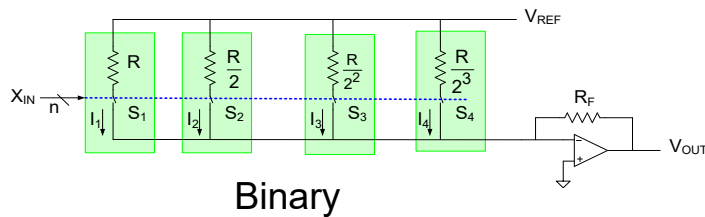
## Segmented Resistor Arrays

- Combines two types of architectures
- Can inherit advantages of both thermometer and binary approach
- Minimizes limitations of both thermometer and binary approach

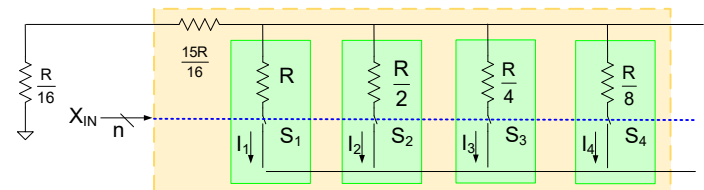
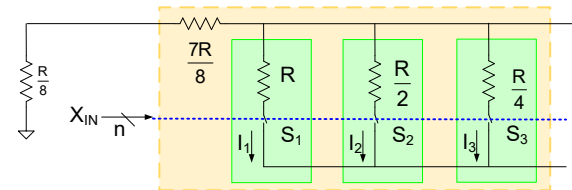
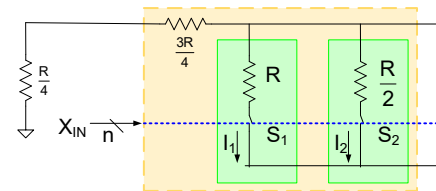
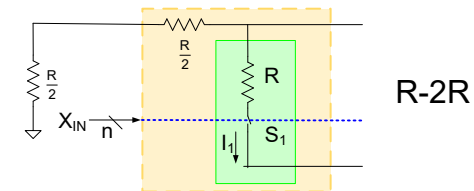


# Current Steering DACs

## Reduced Resistance Structure



## Slice Grouping Options with Series Resistors



Is it better to use series unary cells to form  $R$  or parallel unary cells to form  $\frac{R}{2^n}$  ?

In the two scenarios, is the dominant area allocated to the MSB or the LSB part of the ladder?

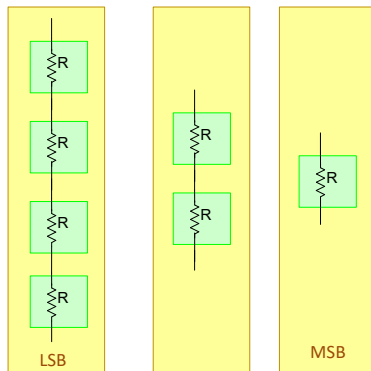
Will this choice make much difference in yield?

What yield-related performance metric will be most affected?

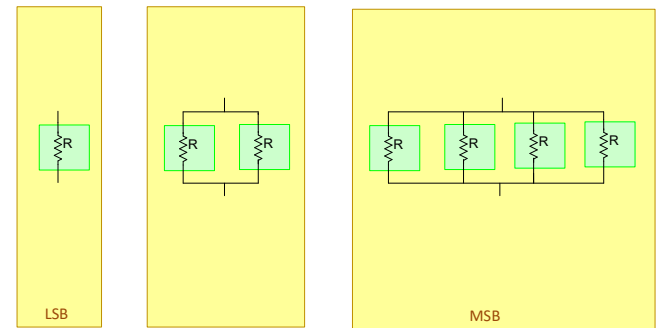
# Current Steering DACs

## Reduced Resistance Structure

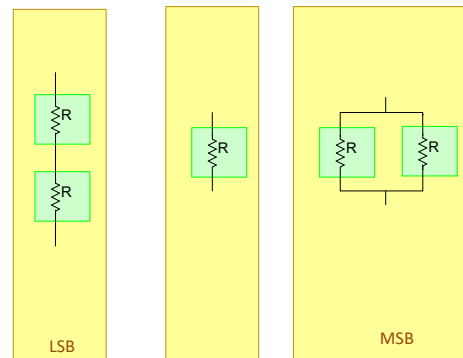
Is it better to use series unary cells to form  $R$  or parallel unary cells to form  $\frac{R}{2^n}$  ?



$2^n - 1$  cells



$2^n - 1$  cells



for n odd  $2^{\frac{n+3}{2}} - 3$  cells

n	Series	Parallel	Split
3	7	7	5
5	31	31	13
7	127	127	29
9	511	511	61
11	2047	2047	125
13	8191	8191	253
15	32767	32767	509

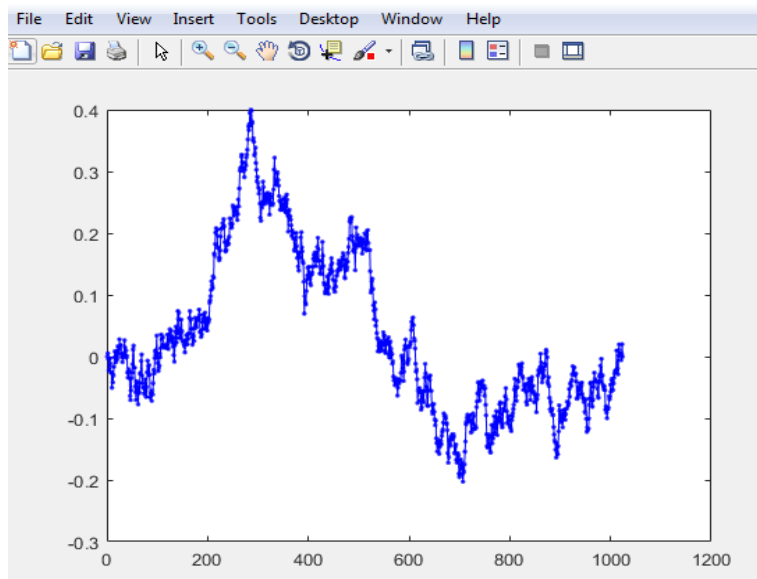
# Comparison of Thermometer Coded and Binary Coded DACs

Example:  $n=10$   
String DAC

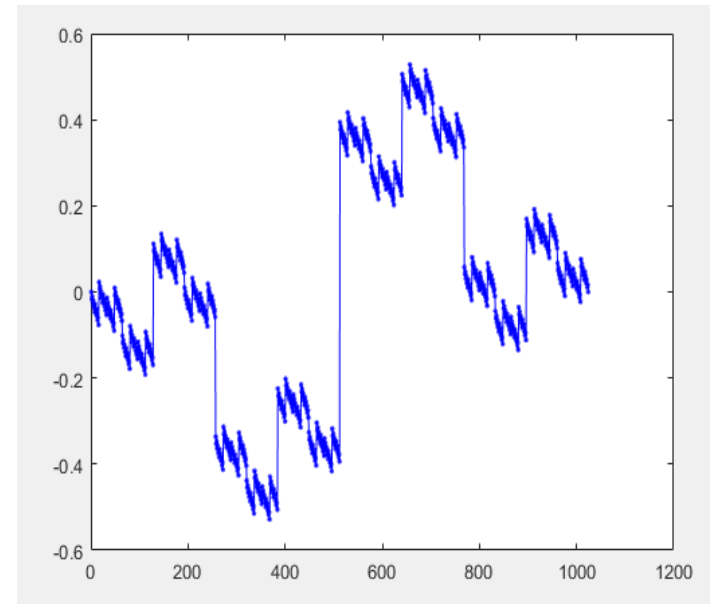
➔  
 $A_R=0.02\mu\text{m}$   
 $R_N=1\text{K}$

Resistor Sigma=  $14.14\ \Omega$

Simulation 1:  $INL_k$



String



Binary Weighted

Actual outputs will differ significantly



Stay Safe and Stay Healthy !

**End of Lecture 16**